Agilent Technologies 8960 Series 10 Wireless Communications Test Set

Manual Operation Guide

Making C.S0033-A Tests Manually

E1966A 1xEV-DO Terminal Test Application Revision: A.06 E6706A 1xEV-DO Lab Application Revision: A.03

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Contents

Introduction
Performing Individual C.S0033-A Tests
Measuring Packet Error Rate (PER)
General Procedure
Testing 3.2.1 Demodulation of Forward Traffic Channel in AWGN
Testing 3.3.1 Receiver Sensitivity and Dynamic Range12
Measuring Access Probe Power
General Procedure .13 Testing 4.3.1 Range of Open Loop Output Power .15
Measuring Graphical Access Probe Power
General Procedure
Measuring Time Response of Open Loop Power Control (TROLPC)
General Procedure
Measuring Digital Average Power
General Procedure
Measuring Channel Power
General Procedure
Measuring Waveform Quality + Code Domain Power
General Procedure
Measuring TX Spurious Emissions
General Procedure.48Testing 4.4.1 Conducted Spurious Emissions.50

Contents

TX Dynamic Power Measurement Description	51
How is a TX Dynamic Power Measurement Made?TX Dynamic Power Measurement ParametersTX Dynamic Power Measurement ResultsTX Dynamic Power Input Signal Requirements	53 55
Calibrating the TX Dynamic Power Measurement	
Fast Device Tune Measurement Description	57
How is a Fast Device Tune Measurement Made?Fast Device Tune Measurement ParametersFast Device Tune Measurement Results	62
Fast Device Tune Input Signal Requirements Calibrating the Fast Device Tune Measurement	65
Appendix	67
Test Adherence to Standards Standards Standards Table Standards	
How Do I Perform a Handoff?	70
How Do I Open a Session and Test Data Connection?	72
A. Configure Call Parameters B. Open a Session C. Open a Test Application Connection	72 73
How Do I Change Call Parameters?	77
General Procedure To Configure the Test Set to FTAP/RTAP Protocols To Configure the Test Set to FETAP/RETAP Protocols To Configure the Test Set to Subtype 0 Physical Layer To Configure the Test Set to Subtype 2 Physical Layer	80 81 82
How Do I Change Cell Parameters?	
A. Select the Cell Parameters Menu.B. Set a Cell Parameter.	

Contents

How Do I Change Access Parameters?	85
General Procedure	85
To Configure the Test Set to Default Access Channel MAC Subtype	
To Configure the Test Set to Enhanced Access Channel MAC Subtype	87
How Do I Change Channel Gain/Traffic Info Parameters?	88
A. Select the Channel Gain Info or Channel Gain/Traffic Info menu	88
B1. Set parameters accessed from F3 (Channel Gain Info)	88
B2. Set parameters accessed from F3 (Channel Gain/Traffic Info)	89
How Do I Change Generator Information?	93
A. Select the Generator Info Menu.	93
B. Set parameters on Gen Info menu.	94
How Do I Change Configurable Attribute Control Mode?	95
A. Select the Configurable Attribute Control Menu.	95
B. Set the Control Mode for a Configurable Attribute.	96
Calibrating the Test Set	97
Description	97
Amplitude Offset	. 105
Description	105

Introduction

The intent of this guide is to help you quickly learn how to use the E1966A and E6706A 1xEV-DO Applications to manually make access terminal receiver and transmitter tests as specified in the C.S0033-A standard.

• See "Performing Individual C.S0033-A Tests" on page 7.

In addition, two measurements that are used for fast calibration on an access terminal are also provided:

- TX Dynamic Power Measurement Description
- Fast Device Tune Measurement Description

The "Appendix" includes additional information to help you perform the C.S0033-A tests:

- Test Adherence to Standards table that shows which tests are supported by the test set.
- General procedures that are required to set up the measurements.
- Calibration procedures that must be performed periodically when testing access terminals with the test set.
- Amplitude Offset information to help you properly account for losses in your system.

The scope of this guide does not cover the numerous features and capabilities of the test set. For additional information, refer to the E1966A/E6706A Online User's Guide which is available at:

- http://wireless.agilent.com/rfcomms/refdocs/1xevdo/, or
- User Documentation CD-ROM shipped with your application.

Performing Individual C.S0033-A Tests

This chapter demonstrates the step-by-step procedures for making the following tests specified in the C.S0033-A standard. The procedures for each test are based on one set of settings as specified for the test. However, the general setup procedures are the same for other sets of settings. To learn more about which tests are supported by the test set, see "Test Adherence to Standards" on page 68.

- "Measuring Packet Error Rate (PER)" on page 8
 - "Testing 3.2.1 Demodulation of Forward Traffic Channel in AWGN" on page 9
 - "Testing 3.2.2 Demodulation of Forward Traffic Channel in Multipath Fading Channel (Lab Application Only)" on page 10
 - "Testing 3.3.1 Receiver Sensitivity and Dynamic Range" on page 12
- "Measuring Access Probe Power" on page 13
 - "Testing 4.3.1 Range of Open Loop Output Power" on page 15
- "Measuring Graphical Access Probe Power" (Lab Application Only)
 - "Testing 4.3.1 Range of Open Loop Output Power"
- "Measuring Time Response of Open Loop Power Control (TROLPC)" on page 24
 - "Testing 4.3.2 Time Response of Open Loop Power Control" on page 26
- "Measuring Digital Average Power" on page 28
 - "Testing 4.3.4 Maximum RF Output Power" on page 29
- "Measuring Channel Power" on page 31
 - "Testing 4.3.5 Minimum Controlled Output Power" on page 32
- "Measuring Waveform Quality + Code Domain Power" on page 34
 - "Testing 4.2.2 Waveform Quality and Frequency Accuracy" on page 40
 - "Testing 4.3.7 RRI Channel Output Power" on page 41
 - "Testing 4.3.8 Code Domain Power" on page 42
 - "Testing 4.3.8.1 DRC Channel Output Power" on page 43
 - "Testing 4.3.8.2 ACK Channel Output Power" on page 43
 - "Testing 4.3.8.3 Data Channel Output Power" on page 44
 - "Testing 4.3.8.4 DSC Channel Output Power" on page 46
- "Measuring TX Spurious Emissions" on page 48
 - "Testing 4.4.1 Conducted Spurious Emissions" on page 50

Measuring Packet Error Rate (PER)

Last updated: July 21, 2006

- "General Procedure"
- "Testing 3.2.1 Demodulation of Forward Traffic Channel in AWGN"
- "Testing 3.2.2 Demodulation of Forward Traffic Channel in Multipath Fading Channel (Lab Application Only)"
- "Testing 3.3.1 Receiver Sensitivity and Dynamic Range"

General Procedure

- 1. Connect the access terminal to the test set's front panel RF IN/OUT connector and power it on.
- 2. Wait for the access terminal to open a session and then open an FTAP (for subtype 0 physical layer) or FETAP (for subtype 2 physical layer) test data connection for AT's receiver test. See "How Do I Open a Session and Test Data Connection?" on page 72 for detailed procedure.
- 3. Set the FTAP Rate (F11) on the Call Parms 1 of 3 menu as needed if during an FTAP connection, or set the F-Traffic Format (F12) on the Call Parms 1 of 3 menu as needed if during an FETAP connection.
- 4. Initialize the PER measurement:
 - Press the **Measurement selection** key.
 - Turn the knob to highlight the Packet Error Rate measurement and press the knob.
- 5. Select Packet Error Rate Setup (F1) to access the Packet Error Rate Setup menu. From this menu you can configure measurement parameters such as Confidence Level, PER Requirement, as well as some general parameters that are required for some C.S0033 tests. For example, you can set AT Directed Packets, which helps you optimize PER test throughput.
- **NOTE** If Limited TAP is on while Test Application Protocol is set to FTAP, AT Directed Packets must not be greater than 50%.

Packet Error Rate Setup	Value
Confidence Level	95.00 %
PER Requirement	1.00 %
Ninimum Packet Count	0
Naximum Packet Count	10000
Control Channel Data Rate	76.8 kbps
AT Directed Packets	50 %
Trigger Arm	Continuous
Neasurement Timeout	Off

6. Select Close Menu (F6) to close the Packet Error Rate Setup window.

7. From the Call Parms menu, configure Cell Power (F7) and FTAP Rate (F11), as needed. See "How Do I Change Call Parameters?" on page 77 for detailed procedure.

NOTE	If Limited TAP is on while Test Application Protocol is set to FTAP, RTAP Rate must be set to 9.6
	kbps.

- 8. From the Call Control menu, configure AWGN Power (F3), as needed. (If you set AWGN Power too high relative to Cell Power, you may drop the connection). See "How Do I Change Generator Information?" on page 93 for detailed procedure.
- 9. Measure PER:
 - If the Trigger Arm field is set to Single, press the START SINGLE key to trigger each measurement.
 - If the Trigger Arm field is set to Continuous the measurement began executing as soon as you initialized it in step 3.

A typical display is shown below:

Packet Error Rate		
Confidence	PER	
Pass	0.00 %	
Packet Error Count:	0	
Packets Tested:	316	
Naximum Packet Count:	10000	
Eb/Nt:	3.77 dB	
PER Requirement:	1.00 %	
		Singl

Testing 3.2.1 Demodulation of Forward Traffic Channel in AWGN

For details on performing the steps below, see the "General Procedure" on page 8 above.

- 1. C.S0033 specifies to set the AN forward packet activity to 100%. Forward packet activity is fixed in the test set, always set to 100%. See Fixed Settings.
- Set the Control Channel Data Rate to 38.4 kbps (see "How Do I Change Cell Parameters?" on page 83).
- 3. C.S0033 specifies to set Pilot Drop to -14 dB. Set Pilot Drop to 28 (see "How Do I Change Cell Parameters?" on page 83). Note that changing the Pilot Drop results in a session re-negotiation.
- 4. Set up a Test Application session and open an FTAP connection for tests 1-18. See "How Do I Open a Session and Test Data Connection?" on page 72 for detailed procedure.
- 5. Initialize the PER measurement.
- 6. Set AT Directed Packets under the Application Config (F10 on Call Parms 1 of 3) menu as needed (In an FTAP connection, if Limited TAP is on, AT Directed Packets must not be greater than 50%,

Measuring Packet Error Rate (PER)

and RTAP Rate must be set to 9.6 kbps).

- 7. Set the ACK Channel Bit Fixed Mode Attribute to Offunder the Application Config (F10 on Call Parms 1 of 3) menu. (Otherwise, you may drop the data connection when AWGN is applied. This recommendation is based on many of experiments.)
- 8. Set \hat{I}_{or} (Cell Power) to -55 dBm/1.23 MHz.
- 9. Set I_{oc} (AWGN Power) and Data Rate/Slots per Physical Layer Packet (FTAP Rate) for tests 1-18 as specified by C.S0033.

For example, in test 15, set the FTAP Data Rate to 307.2 kbps (2 Slot) and set the AWGN Power to -52.5 dBm/1.23 MHz.

10.Set Confidence Level to 95% and PER Requirement as specified by C.S0033.

11.Set Maximum Packet Count as desired.

12.Measure PER for tests 1-18.

- 13.If your AT supports Subtype 2 Physical Layer, continue to measure PER for tests 19-28 and 30 with the following setups.
 - Set Pilot Drop to 32 (corresponding to -16 dB). Note: This results in a session re-negotiation. See "How Do I Change Cell Parameters?" on page 83.
 - Set up a Test Application session and open an FETAP connection. See "How Do I Open a Session and Test Data Connection?" on page 72 for detailed procedure.
 - Set \hat{I}_{or} (Cell Power), I_{oc} (AWGN Power) and forward packet format (packet size, slots, preamble length, data rate) per Physical Layer Packet for tests 19-30 as specified by C.S0033. For example, for test 25, set the Cell Power to -55 dBm/1.23 MHz, the AWGN Power to -47.07 dBm/1.23 MHz. Set the F-Traffic Format to 1 (512, 16, 1024) and the Max Forward Packet Duration to 4 slots which results in the nominal data rate of 19.2 kbps and the effective data rate of 76.8 kbps. (The Max Forward Packet Duration is set from the Termination Parameters menu, see "How Do I Change Generator Information?" on page 93 for detailed procedure).
 - Repeat steps 9 -11 for tests 19-30.

Testing 3.2.2 Demodulation of Forward Traffic Channel in Multipath Fading Channel (Lab Application Only)

This test requires a faded signal with AWGN. When the test set is configured to generate faded forward channel signals with AWGN enabled, it requires a rear panel digital bus connection to an external PC running Baseband Studio software.

The Baseband Studio software is capable of generating fading patterns and AWGN on the forward channel. RF power levels, including AWGN, are controlled by this software. (Note that when the test set is configured to generate a faded signal, the test set's internal AWGN generator is automatically turned off to allow the AWGN to be added by the external fading software. The resulting RF signal from the test set will have fading applied to the forward channel only, with no fading applied to AWGN.)

For detailed setup and operating instructions pertaining to the faded signal generation, refer to the:

E5515C Fading Solution Application Guide

(It can be downloaded at http://cp.literature.agilent.com/litweb/pdf/1000-1894.pdf).

- 1. C.S0033 specifies to set the AN forward packet activity to 100%. Forward packet activity is fixed in the test set, always set to 100%.
- 2. Set the Control Channel Data Rate to 38.4 kbps.
- 3. C.S0033 specifies to set Pilot Drop to -14 dB. Set Pilot Drop to 28 (see "How Do I Change Cell Parameters?" on page 83).
- 4. Set up a Test Application session and open an FTAP connection for tests 1-24. See "How Do I Open a Session and Test Data Connection?" on page 72 for detailed procedure.
- 5. Initialize the PER measurement. (See step 3 of "General Procedure" on page 8.)
- 6. Set up the following key parameters from the Baseband Studio software. For example, for test 1:
 - Set the Cell Band to a value supported by your AT (for example, US PCS).
 - Set the Channel to a value supported by your AT (for example, 425).
 - Set \hat{I}_{or} (Cell Power) to -55 dBm/1.23 MHz.
 - Set I_{oc} (AWGN Power) to -49 dBm/1.23 MHz (for Band 0: US Cellular) or -47.6 dBm/1.23 MHz (for Band 1: US PCS).
 - Select the 1xEV-DO Mobile Station fading configuration Case 1 from the standard Path Config menu.
- 7. Set up the following key parameters from the Packet Error Rate Setup menu on the test set. For example, in test 1 as specified by C.S0033:
 - Set FTAP Rate (Data Rate/Slots per Physical Layer Packet) to 38.4kbps.
 - Set Confidence Level to 95% and PER Requirement to 3.00%.
 - Set Maximum Packet Count as desired.
 - Set Minimum Packet Count to 375 for test 1. (C.S0033 specifies the minimum test duration required for channel simulator configuration 1 is 6000 slots. The test 1 specifies at data rate of 38.4 kbps (16 slots per packet). So the minimum packet count should be 6000/16=375 packets.)
 - Set AT Directed Packets as needed (if Limited TAP is on, AT Directed Packets must not be greater than 50%, and RTAP Rate must be set to 9.6 kbps).
- 8. Measure PER. Repeat the steps 5 7 and change the parameters as required for each of the tests 1-24.
- 9. If your AT supports Subtype 2 Physical Layer, continue to measure PER for tests 25-28 with the following setups.
 - Set up a Test Application session and open an FETAP connection.
 - Follow the above steps 6-7, set \hat{I}_{or} (Cell Power), I_{oc} (AWGN Power) and transmission format (packet size, slots, preamble length, data rate) per Physical Layer Packet for tests 25-28 as specified by C.S0033. For example, for test 25, set the Cell Power to -55 dBm/1.23 MHz, the AWGN Power to -67.5 dBm/1.23 MHz (for Band 0: US Cellular) or -62.5 dBm/1.23 MHz (for Band 1: US PCS). Set the F-Traffic Format to 1 (512, 16, 1024) and the Max Forward Packet Duration to 4 slots which results in the nominal data rate of 19.2 kbps and the effective data rate of 76.8 kbps. (The Max Forward Packet Duration is set from the Termination Parameters menu, see "How Do I Change Generator Information?" on page 93 for detailed procedure).

Testing 3.3.1 Receiver Sensitivity and Dynamic Range

For details on performing the steps below, see the "General Procedure" on page 8 above.

- 1. Set up a Test Application session and open an FTAP or FETAP connection. See "How Do I Open a Session and Test Data Connection?" on page 72 for detailed procedure.
- 2. Initialize the PER measurement.
- 3. Set AT Directed Packets as needed (if in a FTAP connection, Limited TAP is on, AT Directed Packets must not be greater than 50%, and RTAP Rate must be set to 9.6 kbps).
- 4. Receiver Sensitivity (test 1): Set \hat{I}_{or} (Cell Power) to -105.5 dBm/1.23 MHz. Set FTAP Rate to 307.2 (2 Slot) if in an FTAP connection or set F-Traffic Format to 4 (1024, 2, 128) (corresponding to 307.2 kbps) if in an FETAP connection.
- 5. Dynamic Range: Set Î_{or} (Cell Power) to -25 dBm/1.23 MHz. Set FTAP Rate to 307.2 (2 Slot) for test 2 or 2457.6 (1 Slot) for test 3 if in an FTAP connection, or set F-Traffic Format to 4 (1024, 2, 128) for test 2 or C (4096, 1, 64) for test 3 if in an FETAP connection
- 6. Set Confidence Level to 95% and PER Requirement to 0.50%.
- 7. Set Maximum Packet Count as desired.
- 8. Measure PER for each test.

Measuring Access Probe Power

- "General Procedure"
- "Testing 4.3.1 Range of Open Loop Output Power"

General Procedure

- **NOTE** Channel power calibration should be performed if the test set is being used for the first time or the operating environment has changed significantly since the last calibration was performed. The channel power calibration also calibrates the access probe power measurement. See "Calibrating the Test Set" on page 97 for details.
- 1. Connect the access terminal to the test set's front panel **RF IN/OUT** connector and power it on. If the access terminal does not automatically open a session, perform whatever actions are necessary to open a session. See "How Do I Open a Session and Test Data Connection?" on page 72 for more details.
- 2. Initialize the access probe power measurement:
 - Press the **Measurement selection** key.
 - Turn the knob to highlight the Access Probe Power measurement and press the knob.
- 3. Select Access Probe Power Setup (F1) to access the Access Probe Power Setup menu. From this menu you can configure measurement parameters such as Measurement Timeout and Trigger Arm, and also access parameters (such as Open Loop Adjust and Probe Sequence Max), specified for some C.S0033 tests.

Access Probe Power Setup	Value
Open Loop Adjust	81 dB
Probe Initial Adjust	0 dB
Probe Pouer Step	0.0 dB
Probe Num Step	5
Probe Sequence Nax	1
Preamble Length (Frames)	7
Trigger Arm	Continuous
Neasurement Timeout	Off

4. Select Close Menu (F6) to close the Access Probe Power Setup window.

Measuring Access Probe Power

- 5. Set the access network to ignore all access attempts by setting Call Limit Mode to On (F10 on the Call Parms 2 of 3 menu). See "How Do I Change Call Parameters?" on page 77 for more details.
- **NOTE** It is recommended that you always turn Call Limit Mode on when measuring access probe power. The easiest way to induce access probes from the access terminal is to page the access terminal. If you do not have call limit mode set to on, when you page the access terminal, the connection will complete, which clears the access probe power result from the measurement screen.

Set call limit mode back to off when you have finished measuring access probe power.

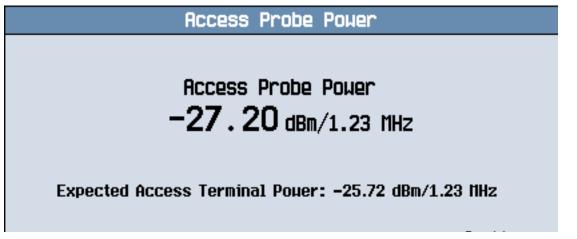
6. If you wish to only capture the first access probe, set Trigger Arm to Single and press the **START SINGLE** key. When the Trigger Arm is set to Continuous, the test set will display the power level of the most recent access probe power measurement. In either case, a measurement result will not be returned until you complete step 7.

IMPORTANT If Trigger Arm is set to Single, you must press the **Start Single** key to arm the measurement. The measurement will not operate until you arm it by pressing the **Start Single** key.

- 7. In order to perform the access probe power measurement, the access terminal must send an access probe. The easiest way to induce this is to page the AT (open a connection) by selecting Start Data Connection (F3 on the Control 2 of 2 menu). When the AT sends an access probe in response the page, its power level will be measured and displayed.
- 8. After finishing the measurements:
 - End the connection attempt by selecting End Data Connection (F3 on the Control 2 of 2 menu).
 - Turn the Call Limit Mode back to Off.
 - Turn the access probe power measurement off by pressing the Measurement selection key, selecting Access Probe Power, then Close Measurement (F4).

IMPORTANT If the access probe power measurement is on and waiting to measure a probe, all other measurements (except digital average power) will not be able to execute. It is therefore recommended that you turn off the access probe power measurement before attempting any other measurements.

A typical display is shown below:



Testing 4.3.1 Range of Open Loop Output Power

For details on performing the steps below, see the "General Procedure" on page 13 above. In the *lab application*, the 4.3.1 test can also be performed with Graphical Access Probe Power measurement, see "Measuring Graphical Access Probe Power" on page 17.

- 1. This test specifies using Default Access Channel MAC Protocol and Access Parameter message. See "To Configure the Test Set to Default Access Channel MAC Subtype" on page 86 for detailed procedure.
- 2. Set the Cell Band and Channel as needed and wait for access terminal automatically opening a session.
- 3. Initialize the access probe measurement.
- 4. Set Probe Power Step to 0 dB. This ensures that all access probes in the probe sequence will transmit at the same power level, rather than incrementing in power. This is beneficial in manual operation if you are running the measurement in continuous mode for the purpose of measuring the power level of all of the probes rather than just the first probe in the sequence.
- 5. Set Probe Sequence Max to 1.
- 6. Set Preamble Length to 7.
- 7. Set Open Loop Adjust to 78 dB or 81 dB, depending upon band class.
- 8. C.S0033 specifies to set the AN forward packet activity to 100%. Forward packet activity is fixed in the test set, always set to 100%.
- 9. Set the access network to ignore all access attempts by setting Call Limit Mode to On.
- 10.Set \hat{I}_{or} (Cell Power) to -25, -65 or approximately -95 dBm/1.23 MHz (value depends on band class and access terminal class) for tests 1-3 as specified by C.S0033.

IMPORTANT If Trigger Arm is set to Single, you must press the **Start Single** key to arm the measurement. The measurement will not operate until you arm it by pressing the **Start Single** key.

- 11.Send a page to the access terminal by selecting Start Data Connection.
- 12.Measure access probe power.

Measuring Access Probe Power

13.Stop the page to the access terminal by selecting Stop Data Connection. 14.Perform steps 10-13 for tests 1-3.

Measuring Graphical Access Probe Power

This section is only applicable to the lab application.

- "General Procedure"
- "Testing 4.3.1 Range of Open Loop Output Power"
- NOTE Channel power calibration should be performed if the test set is being used for the first time or the operating environment has changed significantly since the last calibration was performed. The channel power calibration also calibrates the graphical access probe power measurement. See "Calibrating the Test Set" on page 97 for details.

General Procedure

- 1. Connect the access terminal to the test set's front panel **RF IN/OUT** connector and power it on. If the access terminal does not automatically open a session, perform whatever actions are necessary to open a session. See "How Do I Open a Session and Test Data Connection?" on page 72 for more details.
- 2. Initialize the graphical access probe power measurement:
 - Press the Measurement selection key.
 - Turn the knob to highlight the Graphical Access Probe Power measurement and press the knob.
- 3. Select Graphical Access Probe Pwr Setup (F1) to access the Graphical Access Probe Power Setup menu. Turn the knob to select the parameters and set the value as required for your test situation. For example,
 - set Probe Power Step to 2.0 dB.
 - set Probe Num Step to 6.
 - set Probe Sequence Max to 4.
 - set Preamble Length (Frames) to 7.

NOTE The Probe Sequence Max is a "Configurable Attribute" that is configured during the Session Negotiate State. Its value can not be changed when a session is open and Call Limit Mode is on.

Graphical Access Probe Power Setup	Value
Open Loop Adjust	81 dB
Probe Initial Adjust	0 dB
Probe Pouer Step	2.0 dB
Probe Num Step	6
Probe Sequence Max	4
Preamble Length (Frames)	7
Neasurement Timeout	Off

- 4. Select Close Menu (F6) to close the Graphical Access Probe Power Setup menu.
- 5. Set the access network to ignore all access attempts by setting Call Limit Mode to On (F10 on the Call Parms 2 of 3 menu).

NOTE It is recommended that you always turn all Limit Mode on when measuring graphical access probe power. The easiest way to induce access probes from the access terminal is to page the access terminal. If you do not have call limit mode set to on, when you page the access terminal, the connection will complete, which clears the access probe power result from the measurement screen.

Set call limit mode back to off when you have finished measuring access probe power.

6. Press the **START SINGLE** key to arm the measurement. The measurement result will not be returned until you complete step 7.

IMPORTANT The measurement will not operate until you arm it by pressing the **Start Single** key.

7. In order to perform the graphical access probe power measurement, the access terminal must send access probes. The easiest way to induce this is to page the AT (open a connection) by selecting Start Data Connection (F3 on the Call Control 2 of 2 menu).

Measuring Graphical Access Probe Power

8. When the AT sends access probes as specified in step 3, their power levels will be measured and displayed. As shown below, the measurement results are displayed in both a tabular and a bar graph formats.

Call Control		Graphical Acce	ss Probe F	Power
Operating flode	dBm/1.23 MHz			
Active Cell	30			
	10			
	-10		. 1	
	-30			
End Data Connection				20 5
	Power	- △ Prev _ △ First (dB) (s)]	Power	_ ∆ Prev _ ∆ First (dB) (s)]
Close Session	0 -24.02 1 -21.96 2 -20.21	2.06 0.53 1.75 0.96	10 -15.88 11 -13.94 12 -23.74	1.94 7.47 -9.79 8.64
	2 -20.21 3 -17.91 4 -16.05	2.30 1.60	13 -21.60	2.13 9.07
Handoff Setup _∀	5 -14.05 6 -23.64 7 -21.77	-9.59 3.95 1.87 4.59	15 -17.84 16 -15.84 17 -14.01	2.00 11.20 1.83 11.63
	8 -19.95 9 -17.98	1.82 5.44 1.97 6.19	18 -23.78 19 -21.75	-9.77 12.91
	28 /28			Single
		Active Cell		Sys Type: IS-856
		Paging		Logging: No Conn.

9. (Optional) To adjust the display view, see "Set Up the Graphical View".

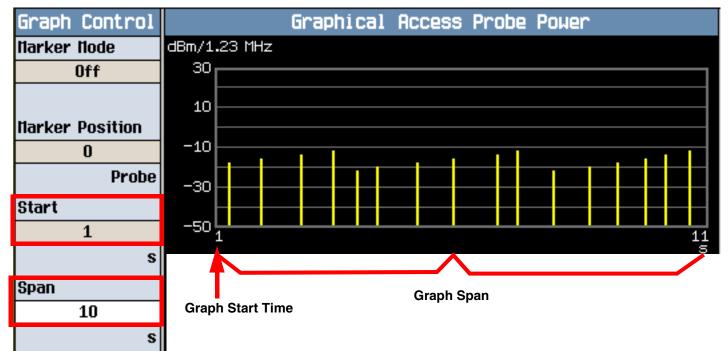
10.After finishing the measurements:

- End the connection attempt by selecting End Data Connection (F3 on the Control 2 of 2 menu).
- Turn the Call Limit Mode back to Off.
- Turn the graphical access probe power measurement off by pressing the **Measurement selection** key, selecting Graphical Access Probe Power, then Close Measurement (F4).

IMPORTANT If the access probe power measurement is on and waiting to measure a probe, all other measurements will not be able to execute. It is therefore recommended that you turn off the graphical access probe power measurement before attempting any other measurements.

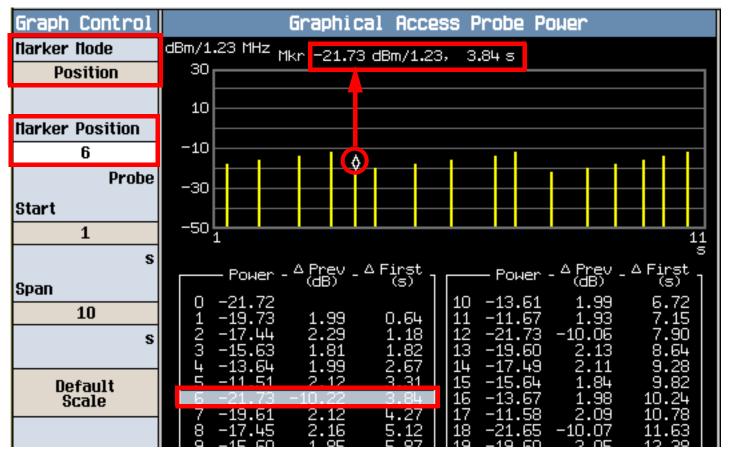
Set Up the Graphical View

- 1. Press the More key on the left side of the display until 1 of 2 is displayed.
- 2. Press the Graph Control (F2) key.
- 3. Select the Start (F3) and Span (F4) to adjust the span of the graph display. The graph window can be adjusted to include the entire 120 second range or only a portion of the 120 second time period of particular interests. The graph can display up to 60 access probes, labeled 0 through 59.



- 4. The Marker Mode (F1) sets the mode of the active marker.
 - When Position is selected, use the Marker Position (F2) to position the marker at any bar across the current span of the graph. Measurement results that correspond with the bar at the position marker (in this example, the power levels for the 7th access probe and the time offset relative to the 1st access

Measuring Graphical Access Probe Power



probe) are displayed above the graph and become highlighted in the table below the graph.

• When Delta is selected, it first freezes the current position marker and uses it as a reference marker. A second marker is created at the position specified by the Delta Position (F2) offset from that of the position marker. Any change in power between the second marker and the position marker is calculated as delta values. Measurement results that correspond with the position marker and the delta marker (in this example, the two values to the right of the "Mkr" indicates the power levels for the 7th access probe and the time offset relative to the 1st access probe, and the two values to the right of the delta symbol indicates the delta power and time between the 9th access probe and the 7th access probe) are displayed

Graph Control	Graphical Access Probe Power
llarker llode	dBm/1.23 MHz Mkr -21.73 dBm/1.23, 3.84 s Δ 4.28 dB, 1.28 s
Delta	30
	10
Marker Delta	
2	
Probe	
Start	
1	
S	
	Power - ^A Prev - ^A First Power - ^A Prev - ^A First (dB) (s) Power - ^(dB) (s) (s)
Span	0 -21.72 10 -13.61 1.99 6.72
10	
s	1 -19.73 1.99 0.64 11 -11.67 1.93 7.15 2 -17.44 2.29 1.18 12 -21.73 -10.06 7.90 3 -15.63 1.81 1.82 13 -19.60 2.13 8.64
	4 -13.64 1.99 2.67 14 -17.49 2.11 9.28
Default Scale	5 -11.51 2.12 3.31 15 -15.64 1.84 9.82 6 -21.73 -10.22 3.84 16 -13.67 1.98 10.24
ocure	<u>] 7 -19.61 2.12 4.27 </u> 17 -11.58 2.09 10.78
	8 -17.45 2.16 5.12 18 -21.65 -10.07 11.63 9 -15.60 1.85 5.87 19 -19.60 2.05 12.38
Return	
	28/28 Singl

above the graph and become highlighted in the table below the graph.

5. (Optional) Press the **MEASUREMENT RESET** key to clear the display.

Testing 4.3.1 Range of Open Loop Output Power

For details on performing the steps below, see the "General Procedure" on page 17 above. The 4.3.1 test can also be performed with Access Probe Power measurement, see "Measuring Access Probe Power" on page 13.

- 1. This test specifies using Default Access Channel MAC Protocol and Access Parameter message. See "To Configure the Test Set to Default Access Channel MAC Subtype" on page 86 for detailed procedure.
- 2. Set the Cell Band and Channel as needed and wait for access terminal automatically opening a session.
- 3. Initialize the graphical access probe measurement.
- 4. Set Probe Power Step to 0 dB. This ensures that all access probes in the probe sequence will transmit at the same power level, rather than incrementing in power.
- 5. Set Probe Sequence Max to 1.
- 6. Set Preamble Length to 7.

- 7. Set Open Loop Adjust to 78 dB or 81 dB, depending upon band class (for example, use 78 for US Cellular band, or use 81 for US PCS band).
- 8. C.S0033 specifies to set the AN forward packet activity to 100%. Forward packet activity is fixed in the test set, always set to 100%.
- 9. Set the access network to ignore all access attempts by setting Call Limit Mode to On.
- 10.Set \hat{I}_{or} (Cell Power) to -25, -65 or approximately -95 dBm/1.23 MHz (value depends on band class and access terminal class) for tests 1-3 as specified by C.S0033.
- 11.Press the **Start Single** key to arm the measurement.

IMPORTANT The measurement will not operate until you arm it by pressing the **Start Single** key.

- 12.Send a page to the access terminal by selecting Start Data Connection.
- 13.Measure access probe power.
- 14.Stop the page to the access terminal by selecting Stop Data Connection.
- 15.Perform steps 10-14 for tests 1-3.

Measuring Time Response of Open Loop Power Control (TROLPC)

- "General Procedure"
- "Testing 4.3.2 Time Response of Open Loop Power Control"

General Procedure

NOTE Channel power calibration should be performed if the test set is being used for the first time or the operating environment has changed significantly since the last calibration was performed. The channel power calibration also calibrates the TROLPC measurement.

- 1. Connect the access terminal to the test set's front panel RF IN/OUT connector and power it on.
- 2. Wait for the access terminal to open a session and then open an RTAP (for subtype 0 physical layer) or RETAP (for subtype 2 physical layer) data connection for AT's transmitter test. See "How Do I Open a Session and Test Data Connection?" on page 72 for detailed procedure.
- 3. Set the RTAP Rate (F12) on the Call Parms 1 of 3 menu as needed if during an RTAP connection, or set the R-Data Pkt Size (F12) on the Call Parms 1 of 3 menu as needed if during an RETAP connection.
- 4. C.S0033 does not specify that the R-ACK Channel must be active for 4.3.2 Time Response of Open Loop Power Control. If the R-ACK Channel is active during this test, the access terminal's power may fall outside of the mask specifications. To help ensure that your access terminal does not fail this test, you should disable the R-ACK Channel by setting the following parameters from the Application Config (F10 on the Call Parms 1 of 3):
 - Set ACK Channel Bit Fixed Mode Attribute to Off.
 - Set AT Directed Packets to 0%.

IMPORTANT After completing TROLPC testing, you must return ACK Channel Bit Fixed Mode Attribute to on and set AT Directed Packets to a non-zero value, if needed.

- 5. Initialize the TROLPC measurement:
 - Press the **Measurement selection** key.
 - Turn the knob to highlight the Time Response of Open Loop Power Control measurement and press the knob.

NOTE If any measurements are open during initiation of a TROLPC, the test set will automatically close them and display an error message indicating the last measurement that was closed.

6. Select Time Response of OLPC Setup (F1) to access the Time Response of OLPC Setup menu. You

Measuring Time Response of Open Loop Power Control (TROLPC)

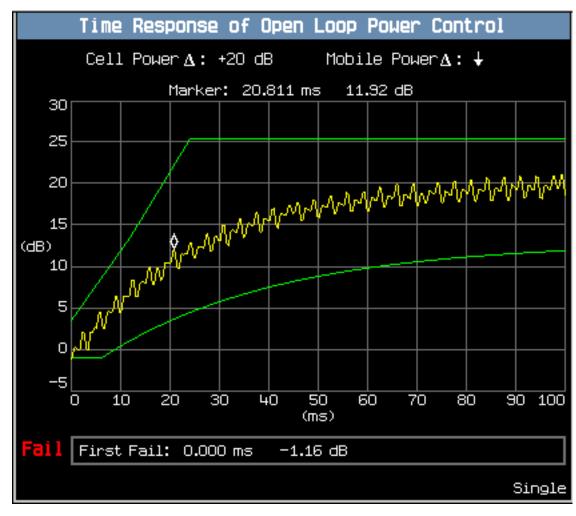
can also configure AT directed packets and ACK channel bit fixed mode attribute from this menu.

Time Response of OLPC Setup	Value
AT Directed Packets	50 %
ACK Channel Bit Fixed Node Attribute	Off
Neasurement Timeout	0ff

- 7. Select Close Menu $({\bf F6})$ to close the Time Response of OLPC Setup window.
- 8. From the Call Parms menu, configure Cell Power (F7), as needed.
- 9. Measure TROLPC:
 - Select Start Meas Up (F2), which automatically increases Cell Power by 20 dB and captures the resulting access terminal output power for 100 ms, or
 - Select Start Meas Down (F3) which automatically decreases Cell Power by 20 dB and captures the resulting access terminal output power for 100 ms.
 - You may also select START SINGLE to start the measurement. The cell power will increase by 20 dB if Start Meas Up was last performed (or if the test set is in a preset state), or decrease by 20 dB if Start Meas Down was last performed.
- 10.After the measurement has completed, select Marker (F4) and turn the knob to display power at points along the access terminal output power trace. If the test failed, next to the word "Fail," the first data point at which the test failed is displayed.

NOTE As specified by C.S0033, the AT output power level curve is shown in absolute terms. The delta expressions above the display indicate the direction of power change.

Measuring Time Response of Open Loop Power Control (TROLPC)



An example of a "Fail" test result is shown below.

IMPORTANT After completing TROLPC testing, you must return ACK Channel Bit Fixed Mode Attribute to on and set AT Directed Packets to a non-zero value appropriate for your test setup.

Testing 4.3.2 Time Response of Open Loop Power Control

For details on performing the steps below, see the "General Procedure" on page 24 above.

1. For Subtype 0 or 1 Physical Layer, set up a Test Application session and open an RTAP connection with the RTAP Rate set to 9.6 kbps. For detailed procedure on how to open an RTAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72.

For Subtype 2 Physical Layer, set up a Test Application session and open an RETAP connection with the following setups. For detailed procedure on how to open an RETAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72.

- Set the R-Data Pkt Size (F12 on Call Parms 1 of 3) to 256 bits.
- Set the Reverse Data Transmission Mode under the Application Config (F10 on Call Parms 1 of

3) menu to High Capacity.

- From the Power Parameters Info menu (see "How Do I Change Channel Gain/Traffic Info Parameters?" on page 88 for how to access), set the 256-bit High Capacity Termination Target to 3 (4 sub-frames, 16 slots). (NOTE: You do not need to set these settings unless the default value (3) of these settings are changed. Changing these setting results in an open data connection closed because these settings are configured during session negotiation. Once this happen, you need to re-open the connection.)
- 2. Configure the Test Application FTAP (for Subtype 0 or 1 Physical Layer) or FETAP (for Subtype 2 Physical Layer) so that the ACK Channel is not transmitted by the access terminal, by setting ACK Channel Bit Fixed Mode Attribute to Off and AT Directed Packets to 0% under the Application Config (F10 on Call Parms 1 of 3) menu.
- 3. Initialize the TROLPC measurement.
- 4. Set \hat{I}_{or} (Cell Power) to -60 dBm/1.23 MHz.
- 5. C.S0033 specifies to send alternating '0' and '1' power control bits on the Forward Traffic Channel. When you start the TROLPC measurement, the test set automatically sends alternating closed loop power control bits during the test.
- 6. Measure TROLPC:
 - Select Start Meas Up (F2), (cell power transitions to -40 dBm/1.23 MHz), and note the pass/fail result.
 - Select Start Meas Down (F3), (cell power transitions to -60 dBm/1.23 MHz), and note the pass/fail result.
 - Select Start Meas Down (F3), (cell power transitions to -80 dBm/1.23 MHz), and note the pass/fail result.
 - Select Start Meas Up (F2), (cell power transitions to -60 dBm/1.23 MHz), and note the pass/fail result.

Measuring Digital Average Power

- "General Procedure"
- "Testing 4.3.4 Maximum RF Output Power"

General Procedure

NOTE Digital average power calibration should be performed if the test set is being used for the first time or the operating environment has changed significantly since the last calibration was performed.

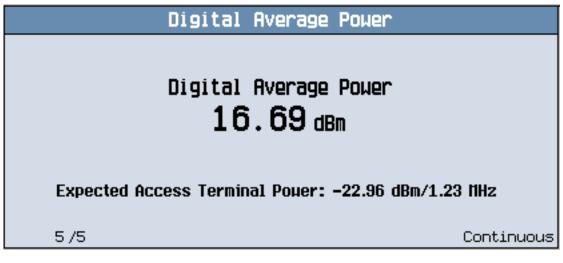
- 1. Connect the access terminal to the test set's front panel RF IN/OUT connector and power it on.
- 2. Wait for the access terminal to open a session and then open an RTAP (for subtype 0 physical layer) or RETAP (for subtype 2 physical layer) data connection for AT's transmitter test. See "How Do I Open a Session and Test Data Connection?" on page 72 for detailed procedure.
- 3. Set the RTAP Rate (F12) or FTAP Rate (F11) on the Call Parms 1 of 3 menu as needed if during an RTAP connection, or set the R-Data Pkt Size (F12) or F-Traffic Format (F11) on the Call Parms 1 of 3 menu as needed if during an RETAP connection.
- 4. Initialize the digital average power measurement:
 - Press the **Measurement selection** key.
 - Turn the knob to highlight the Digital Average Power measurement and press the knob.
- 5. Select Digital Average Power Setup (F1) to access the Digital Average Power Setup menu. From this menu you can configure measurement parameters such as Multi-Measurement Count and Trigger Arm. For statistical measurement results, highlight the Multi-Measurement Count parameter and press the ON key. The number of averages will default to 10. You can change the number as desired.

Digital Average Power Setup	Value
Nulti-Neasurement Count	5
Trigger Arm	Single
Neasurement Timeout	1.0 s

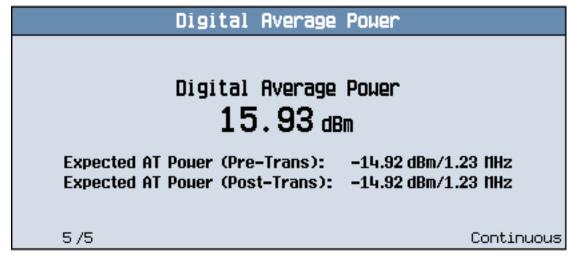
6. Select Close Menu (F6) to close the Digital Average Power Setup window.

- 7. From the Call Parms menu, configure Cell Power (F7), as needed.
- 8. Measure digital average power:
 - If the Trigger Arm field is set to Single, press the START SINGLE key to trigger each measurement.
 - If the Trigger Arm field is set to Continuous, the measurement began executing as soon as you initialized it in step 3.

A typical measurement result (for subtype 0 physical layer) is shown below:



A typical measurement result (for subtype 2 physical layer) is shown below:



Testing 4.3.4 Maximum RF Output Power

For details on performing the steps below, see the "General Procedure" on page 28 above.

- 1. Initialize the digital average power measurement.
- 2. Set the following access parameters (see "How Do I Change Access Parameters?" on page 85):
 - Set Open Loop Adjust to 81 dB or 84 dB, depending upon band class. (for example, 81 for US Cellular band or 84 for US PCS band)

- Set Probe Initial Adjust to 15 dB.
- Set Probe Power Step to 7.5 dB/step.
- 3. For Subtype 0 or 1 Physical Layer, set up a Test Application session and open an RTAP connection with the RTAP Rate set to 153.6 kbps. For detailed procedure on how to open an RTAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72.

For Subtype 2 Physical Layer, set up a Test Application session and open an RETAP connection with the following setups. For detailed procedure on how to open an RETAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72.

- Set the R-Data Pkt Size (F12 on Call Parms 1 of 3) to 4096 bits.
- Set the Reverse Data Transmission Mode under the Application Config (F10 on Call Parms 1 of 3) menu to High Capacity.
- From the Power Parameters Info menu (see "How Do I Change Channel Gain/Traffic Info Parameters?" on page 88 for how to access), set the 4096-bit High Capacity Termination Target to 3 (4 sub-frames, 16 slots). (NOTE: You do not need to set these settings unless the default value (3) of these settings are changed. Changing these setting results in an open data connection closed because these settings are configured during session negotiation. Once this happen, you need to re-open the connection.)
- 4. C.S0033 specifies to configure the Test Application FTAP (for Subtype 0 or 1 Physical Layer) or FETAP (for Subtype 2 Physical Layer) with a Forward Traffic Channel rate of 307.2 kbps (2-slot version) and the ACK Channel is transmitted at all the slots. To do this, set the FTAP Rate (F11 on Call Parms 1 of 3) to 307.2 (2 Slot) if during subtype 0

physical layer test or set the F-Traffic Format (F11 on Call Parms 1 of 3) to 4 (1024, 2, 128) if during subtype 2 physical layer test, and set ACK Channel Bit Fixed Mode to On from Application Config (F10 on Call Parms 1 of 3).

- 5. Set \hat{I}_{or} (Cell Power) to -60 dBm/1.23 MHz.
- 6. Set Rvs Power Ctrl to All Up bits (F7 on the Call Parms 2 of 3 menu) to transmit continuous up power control bits.
- 7. Measure digital average power.
- 8. When you have finished testing, be sure to set the Rvs Power Ctrl back to Active bits to ensure that subsequent signalling is successful.

Measuring Channel Power

- "General Procedure"
- "Testing 4.3.5 Minimum Controlled Output Power"

General Procedure

NOTE Channel power calibration should be performed if the test set is being used for the first time or the operating environment has changed significantly since the last calibration was performed.

- 1. Connect the access terminal to the test set's front panel RF IN/OUT connector and power it on.
- 2. Wait for the access terminal to open a session and then open an RTAP (for subtype 0 physical layer) or RETAP (for subtype 2 physical layer) data connection for AT's transmitter test.
- 3. Set the RTAP Rate (F12) on the Call Parms 1 of 3 menu as needed if during an RTAP connection, or set the R-Data Pkt Size (F12) on the Call Parms 1 of 3 menu as needed if during an RETAP connection.
- 4. Initialize the channel power measurement:
 - Press the Measurement selection key.
 - Turn the knob to highlight the Channel Power measurement and press the knob.
- 5. Select Channel Power Setup (F1) to access the Channel Power Setup menu. From this menu you can configure measurement parameters such as Multi-Measurement Count, Trigger Arm, etc. For statistical measurement results, highlight the Multi-Measurement Count parameter and press the ON key. The number of averages will default to 10. You can change the number as desired.

Channel Power Setup	Value	
Nulti-Neasurement Count	5	
Trigger Arm	Continuous	
Neasurement Speed	Fast	
Neasurement Timeout	Off	

- 6. Select Close Menu (F6) to close the Channel Power Setup window.
- 7. From the Call Parms menu, configure Cell Power (F7), as needed.
- 8. Measure channel power:

Measuring Channel Power

- If the Trigger Arm field is set to Single, press the START SINGLE key to trigger each measurement.
- If the Trigger Arm field is set to Continuous the measurement began executing as soon as you initialized it in step 3.

A typical measurement result (for subtype 0 physical layer) is shown below:

Channel Power				
Channel Pouer (dBm/1.23 MHz)	11inimum -26.0247	Naximum -25.8198	Average -25.9013	
Expected Access Terminal Pouer: -22.96 dBm/1.23 MHz Neasurement Speed: Fast				
5/5			Continuous	

A typical measurement result (for subtype 2physical layer) is shown below:

Channel Power				
	Hinimum	Haximum	Average	
Channel Pouer (dBm/1.23 fiHz)	-25.3584	-23.2826	-24.4215	
COBM/1.23 HHZ) Expected AT Pouer (Pre-Trans): -22.21 dBm/1.23 HHz Expected AT Pouer (Post-Trans): -22.21 dBm/1.23 HHz Ileasurement Speed: Fast 5/5 Continuous				

Testing 4.3.5 Minimum Controlled Output Power

For details on performing the steps below, see the "General Procedure" on page 31 above.

1. For Subtype 0 or 1 Physical Layer, set up a Test Application session and open an RTAP connection with the RTAP Rate set to 9.6 kbps. For detailed procedure on how to open an RTAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72

For Subtype 2 Physical Layer, set up a Test Application session and open an RETAP connection with the following setups. For detailed procedure on how to open an RETAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72.

• Set the R-Data Pkt Size (F12 on Call Parms 1 of 3) to $256 \; bits.$

- Set the Reverse Data Transmission Mode under the Application Config (F10 on Call Parms 1 of 3) menu to High Capacity.
- From the Power Parameters Info menu (see "How Do I Change Channel Gain/Traffic Info Parameters?" on page 88 for how to access), set the 256-bit High Capacity Termination Target to 3 (4 sub-frames, resulting in 16 slots). (NOTE: You do not need to set this parameter unless its default value (3) is changed. Changing the setting results in an open data connection closed and a session re-negotiation. Once this happen, you need to re-open the connection.)
- 2. Initialize the channel power measurement.
- 3. Set the Call Drop Timer to Off (F9 on the Call Parms 2 of 3 menu) to keep the test set from closing the connection based on the very low output power level of the access terminal.
- 4. Set \hat{I}_{or} (Cell Power, F7 on the Call Parms 1 of 3 menu) to -25 dBm/1.23 MHz.
- 5. Set Rvs Power Ctrl to All Down bits (F7 on the Call Parms 2 of 3 menu) to transmit continuous down ('1') power control bits.
- 6. Measure channel power.
- **NOTE** If Under Range is posted, it indicates that the measured power is below -61 dBm or is less than -9 dB below the expected power level of the receiver. When this happens, you should manually adjust the test sets receiver power and then repeat the test. (Setup procedure: on Call Parms 1 of 3 menu, select Manual in the Rcvr Power Ctrl (**F8**), then set the Receiver Power (**F9**) to a value close to the measured value being displayed on the Channel Power measurement screen.)
- 7. When you have finished the testing, be sure to set the Call Drop Timer back to On and the Rvs Power Ctrl back to Active Bits to ensure that subsequent operation is successful.

Measuring Waveform Quality + Code Domain Power

Last updated: July 21, 2006

- "General Procedure" on page 34
- "Testing 4.2.2 Waveform Quality and Frequency Accuracy" on page 40
- "Testing 4.3.7 RRI Channel Output Power" on page 41
- "Testing 4.3.8 Code Domain Power" on page 42

General Procedure

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NOTE Channel power calibration should be performed if the test set is being used for the first time or the operating environment has changed significantly since the last calibration was performed. The channel power calibration also calibrates the waveform quality + code domain measurement.
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- 1. Connect the access terminal to the test set's front panel RF IN/OUT connector and power it on.
- 2. Wait for the access terminal to open a session and then open an RTAP (for subtype 0 physical layer) or RETAP (for subtype 2 physical layer) data connection for AT's transmitter test. See "How Do I Open a Session and Test Data Connection?" on page 72 for detailed procedure.
- 3. Set the RTAP Rate (F12) or FTAP Rate (F11) on the Call Parms 1 of 3 menu as needed if during an RTAP connection, or set the R-Data Pkt Size (F12) or F-Traffic Format (F11) on the Call Parms 1 of 3 menu as needed if during an RETAP connection.
- 4. Initialize the waveform quality + code domain measurement:
 - Press the **Measurement selection** key.
 - Turn the knob to highlight the Waveform Quality + Code Domain measurement and press the knob.
- 5. Select Waveform Quality + Code Domain Setup (F1) to access the Waveform Quality + Code Domain Setup menu. From this menu you can configure measurement parameters such as Slots to Measure, DRC Channel Gain, etc. For statistical measurement results, highlight the

Measuring Waveform Quality + Code Domain Power

Waveform Quality Setup	Value -	For Subtype 0 Physical Layer
Nulti-Neasurement Count	Off	
Slots To Neasure	1	1
Ack Channel Gain	3.0 dB	
DRC Channel Gain	3.0 dB	
Trigger Arm	Continuous	
Neasurement Timeout	Off	
Waveform Quality Setup	Value -	For Subtype 2 Physical Layer
Nulti-Neasurement Count	Off	
Slots To Neasure	1]
ACK Channel Gain	3.0 dB]
DRC Channel Gain	3.0 dB]
DSC Channel Gain	-9.0 dB	This parameter is only available for
Trigger Arm	Continuous	Subtype 2 Physical
Neasurement Timeout	Off	Layer.

Multi-Measurement Count parameter and press the ON key. The number of averages will default to 10.

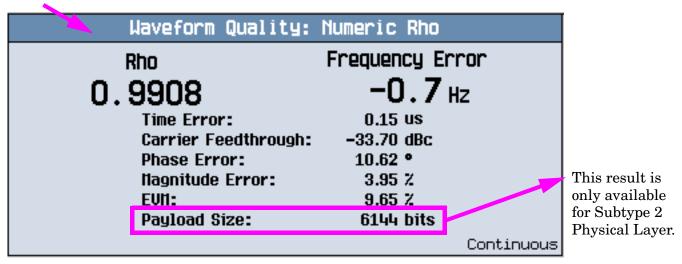
- 6. Select Close Menu (F6) to close the Waveform Quality + Code Domain Setup window.
- 7. If needed, set the RTAP Rate (F12) or FTAP Rate (F11) on the Call Parms 1 of 3 menu when during an RTAP connection test, or set the R-Data Pkt Size (F12) or F-Traffic Format (F11) on the Call Parms 1 of 3 menu when during an RETAP connection test.
- 8. Measure waveform quality and code domain power:
 - If the Trigger Arm field is set to Single, press the START SINGLE key to trigger each measurement.
 - If the Trigger Arm field is set to Continuous, the measurement began executing as soon as you initialized it in step 3.

Measuring Waveform Quality + Code Domain Power

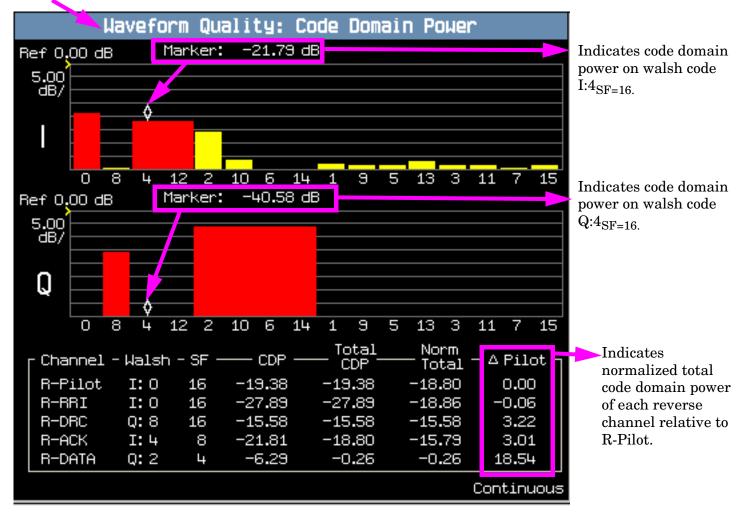
9. Select Numeric Rho (F2) to view the waveform quality results. A typical display is shown below. Subtype 0 Physical Layer Waveform Quality Numeric Rho Result Display

Waveform Quality:	Numeric Rho	
Rho	Frequency Error	
0.9940	-6.8 Hz	
Time Error:	-0.05 us	
Carrier Feedthrough:	-44.29 dBc	
Phase Error:	4.78 °	
Nagnitude Error:	2.15 %	
EVII:	7.79 %	
		Single

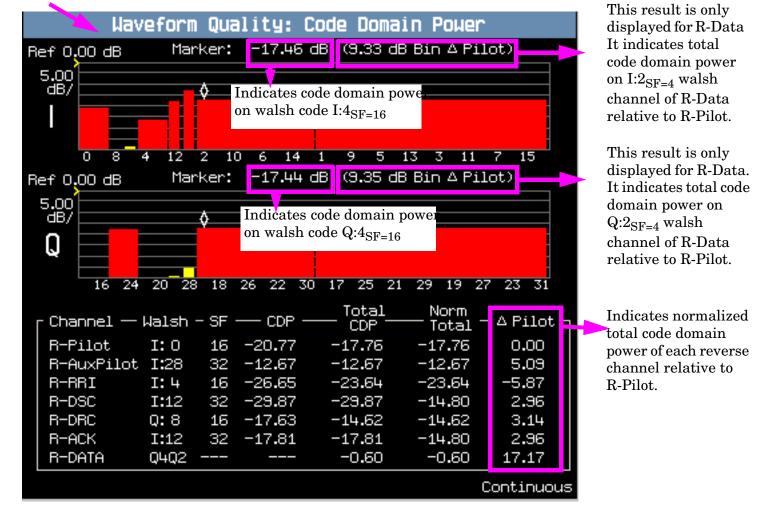
Subtype 2 Physical Layer Waveform Quality Numeric Rho Result Display



10.Select Code Domain Power (F3) to view the code domain results. A typical display is shown below. When viewing the code domain results, you can select Marker Position (F6) and turn the knob to select a Walsh code and display its power.

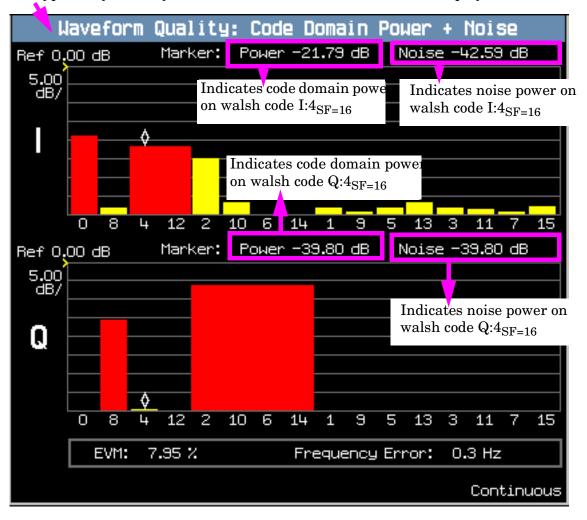


Subtype 0 Physical Layer Code Domain Power Result Display

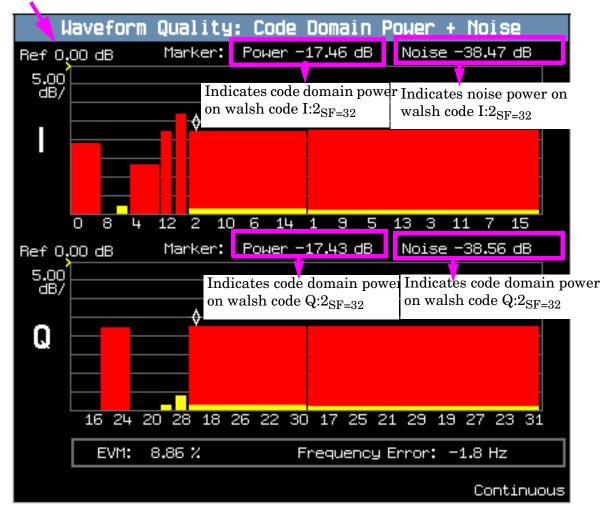


Subtype 2 Physical Layer Code Domain Power Result Display

11.Select Code Domain Power + Noise (F4) to view the code domain + noise results. A typical display is shown below. When viewing the code domain + noise results, you can select Marker Position (F6) and turn the knob to select a Walsh code and display its power.



Subtype 0 Physical Layer Code Domain Power + Noise Result Display



Subtype 2 Physical Layer Code Domain Power + Noise Result Display

Testing 4.2.2 Waveform Quality and Frequency Accuracy

For details on performing the steps below, see the "General Procedure" on page 34 above.

1. For Subtype 0 or 1 Physical Layer, set up a Test Application session and open an RTAP connection with the RTAP Rate set to 9.6 kbps. For detailed procedure on how to open an RTAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72.

For Subtype 2 Physical Layer, set up a Test Application session and open an RETAP connection with the following setups. For detailed procedure on how to open an RETAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72.

- Set the R-Data Pkt Size (F12 on Call Parms 1 of 3) to 256 bits.
- Set the Reverse Data Transmission Mode under the Application Config (F10 on Call Parms 1 of 3) menu to High Capacity.
- From the Power Parameters Info menu (see "How Do I Change Channel Gain/Traffic Info Parameters?"

on page 88 for how to access), set the 256-bit High Capacity Termination Target to 3 (4 sub-frames, 16 slots). (NOTE: You do not need to set these settings unless the default value (3) of these settings are changed. Changing these setting results in an open data connection closed because these settings are configured during session negotiation. Once this happen, you need to re-open the connection.)

- 2. C.S0033 specifies to configure the FTAP or FETAP such that the ACK Channel is transmitted at all the slots. To do this, set the ACK Channel Bit Fixed Mode to On from Application Config (F10 under Call Parms 1 of 3).
- 3. Initialize the waveform quality + code domain measurement. Set Slots to Measure to 1.
- 4. Set \hat{I}_{or} (Cell Power) to -75 dBm/1.23 MHz.
- 5. Measure waveform quality + code domain.
- 6. Select Numeric Rho (F2) to view the Rho, Frequency Error and Time Error results. A typical measurement result is shown below.

	Waveform Quality: Numeric Rho								
	Rho 0.9933		סה		Error				
				0.9	9 Hz				
	Time Error:			0.42 US					
		Carrier F	eedthrough:	-32.81 dBa					
		Phase Err	ror:	11.81 °					
		Nagnitude	Error:	3.60 %					
EVII:				8.18 %					
Payload Size		Size:	256 bit	5					
					Cor	ntinuous			

Testing 4.3.7 RRI Channel Output Power

For details on performing the steps below, see the "General Procedure" on page 34 above.

- 1. Test 1: Set up a Test Application session and open an RTAP connection (for Subtype 0 or 1 Physical Layer).
- 2. Set \hat{I}_{or} (Cell Power) to -75 dBm/1.23 MHz.
- 3. Initialize the waveform quality + code domain measurement.
- 4. Set Slots to Measure to 8.
- 5. Measure waveform quality + code domain.
- 6. Select Code Domain Power (F3) to view the R-RRI Δ Pilot result (available in the last column of the table of data).
- 7. Test 2: Set up an RETAP session (for Subtype 2 Physical Layer) with the following parameters and then open an RETAP connection. For detailed procedure on how to open an RETAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72. (NOTE: It is recommended set the parameters prior to opening the session and connection because some of these settings are configured

during session negotiation state)

- Set the R-Data Pkt Size (F12 on Call Parms 1 of 3) to $256 \ bits.$
- Set the Reverse Data Transmission Mode under the Application Config (F10 on Call Parms 1 of 3) menu to High Capacity.
- From the Power Parameters Info menu (see "How Do I Change Channel Gain/Traffic Info Parameters?" on page 88 for how to access), set the 256-bit High Capacity T2P Transition to 3 (4 sub-frames) and 256-bit High Capacity Termination Target to 3 (4 sub-frames). (NOTE: You do not need to set these settings unless the default value (3) of these settings are changed. Changing these setting results in an open data connection closed because these settings are configured during session negotiation. Once this happen, you need to re-open the connection.)
- From the RRI Gain Parameters Info menu (see "How Do I Change Channel Gain/Traffic Info Parameters?" on page 88 for how to access), set the RRI Channel Gain Pre-Transition 3 to -6 dB and 256-bit High Capacity Termination Target to 3 (4 sub-frames). (NOTE: You do not need to set these settings unless the default value (3) of these settings are changed. Changing these setting results in an open data connection closed because these settings are configured during session negotiation. Once this happen, you need to re-open the connection.)
- 8. Set Slots to Measure to 1.
- 9. Measure waveform quality + code domain.
- 10.Select Code Domain Power (F3) to view the R-RRI Δ Pilot result (available in the last column of the table of data).

r Channel —	Walsh	- SF		Total CDP	— Norm Total ·	- △ Pilot ק	
R-Pilot	I: 0	16	-11.23	-8.22	-8.22	0.00	
R-AuxPilot							Verify that this result
R-RRI	I:4	16	-17.27	-14.26	-14.26	-6.04 -	should be within +/-
R-DSC	I:12	32	-20.30	-20.30	-5.15	3.06	0.25 dB of the RRI
R-DRC	Q:8	16	-8.34	-5.33	-5.33	2.89	Channel Gain
R-ACK	I:12	32	-8.17	-8.17	-5.15	3.06	Pre-Transition 3
R-DATA	Q:2	4	-13.58	-4.55	-4.55	3.67	setting.

11.A typical measurement result for test 2 is shown below.

Testing 4.3.8 Code Domain Power

For details on performing the steps below, see the "General Procedure" on page 34 above.

- "Testing 4.3.8.1 DRC Channel Output Power" on page 43
- "Testing 4.3.8.2 ACK Channel Output Power" on page 43
- "Testing 4.3.8.3 Data Channel Output Power" on page 44
- "Testing 4.3.8.4 DSC Channel Output Power" on page 46

Testing 4.3.8.1 DRC Channel Output Power

- 1. Set up a Test Application session and open an RTAP (for Subtype 0 or 1 Physical Layer) or an RETAP (for Subtype 2 Physical Layer) connection. See "How Do I Open a Session and Test Data Connection?" on page 72 for detailed procedure.
- 2. C.S0033 specifies to configure the FTAP or FETAP such that the ACK Channel is transmitted at all the slots. To do this, set the ACK Channel Bit Fixed Mode to On from Application Config (F10 under Call Parms 1 of 3).
- 3. Set \hat{I}_{or} (Cell Power) to -75 dBm/1.23 MHz.
- 4. Initialize the waveform quality + code domain measurement. Set the Slots to Measure to 2 if during a RTAP connection (for subtype 0 physical layer test) or set the Slots to Measure to 1 if during a RETAP connection (for subtype 2 physical layer test).
- 5. Set DRC Channel Gain to 0 dB.
- 6. Measure waveform quality + code domain.
- 7. Select Code Domain Power (F3) to view the R-DRC Δ Pilot result (available in the last column of the table of data).
- 8. Set DRC Channel Gain to 3 dB and repeat steps 6 and 7.
- 9. A typical measurement result is shown below.

r Channel —	– Walsh	- SF	- CDP ·	Total CDP		- A Pilot -	1
R-Pilot	I: 0	16	-11.23	-8.22	-8.22	0.00	
R-AuxPilo	t						Veri
R-BRI	I:4	16	-17.27	-14.26	-14.26	-6.04	shou
R-DSC	I:12	32	-20.30	-20.30	-5.15	3.06	0.25
R-DRC	Q:8	16	-8.34	-5.33	-5.33	2.89	Cha
R-ACK	I:12	32	-8.17	-8.17	-5.15	3.06	
R-DATA	Q:2	4	-13.58	-4.55	-4.55	3.67	

Verify that this result should be within +/-0.25 dB of the DRC Channel Gain setting.

Testing 4.3.8.2 ACK Channel Output Power

- 1. Set up a Test Application session and open an RTAP (for Subtype 0 or 1 Physical Layer) or an RETAP (for Subtype 2 Physical Layer) connection. See "How Do I Open a Session and Test Data Connection?" on page 72 for detailed procedure.
- 2. C.S0033 specifies to configure the FTAP or FETAP such that the ACK Channel is transmitted at all the slots. To do this, set the ACK Channel Bit Fixed Mode to On from Application Config (F10 under Call Parms 1 of 3).
- 3. Set \hat{I}_{or} (Cell Power) to -75 dBm/1.23 MHz.
- 4. Initialize the waveform quality + code domain measurement. Set Slots to Measure to 2.
- 5. Set ACK Channel Gain to $0\;dB.$
- 6. Measure waveform quality + code domain.

- 7. Select Code Domain Power (F3) to view the R-ACK Δ Pilot result (available in the last column of the table of data).
- 8. Set ACK Channel Gain to 3 dB and repeat steps 6 and 7.
- 9. A typical measurement result is shown below.

_C Channel —	Walsh	- SF	- CDP ·	Total CDP -		– △ Pilot _–
R-Pilot	I: 0	16	-11.23	-8.22	-8.22	0.00
R-AuxPilot						
R-RRI	I:4	16	-17.27	-14.26	-14.26	-6.04
R-DSC	I:12	32	-20.30	-20.30	-5.15	3.06
R-DRC	Q:8	16	-8.34	-5.33	-5.33	2.89
R-ACK	I:12	32	-8.17	-8.17	-5.15	3.06
R-DATA	Q:2	4	-13.58	-4.55	-4.55	3.67

Verify that this result should be within +/-0.25 dB of the ACK Channel Gain setting.

Testing 4.3.8.3 Data Channel Output Power

The test set currently does not support tests 6 and 7 for measuring the capsule portion of each Access Channel probe.

1. For Subtype 0 or 1 Physical Layer, set up a Test Application session and open an RTAP connection with the RTAP Rate set to 9.6 kbps. For detailed procedure on how to open an RTAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72.

For Subtype 2 Physical Layer, set up a Test Application session and open an RETAP connection with the following setups. For detailed procedure on how to open an RETAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72.

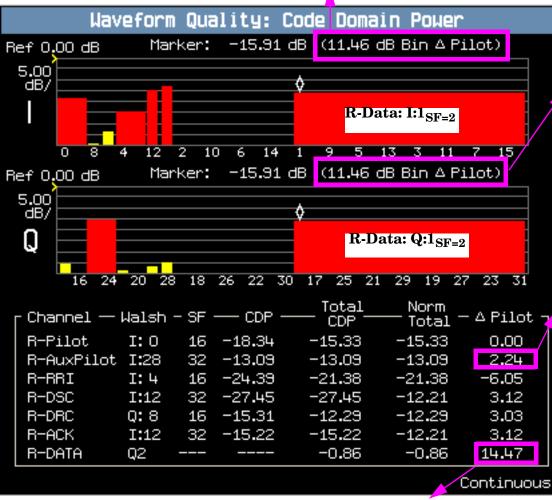
- Set the R-Data Pkt Size (F12 on Call Parms 1 of 3) to $256 \; bits.$
- Set the Reverse Data Transmission Mode under the Application Config (F10 on Call Parms 1 of 3) menu to High Capacity.
- From the Power Parameters Info menu (see "How Do I Change Channel Gain/Traffic Info Parameters?" on page 88 for how to access), set the 256-bit High Capacity Termination Target to 3 (4 sub-frames, resulting in 16 slots). (NOTE: You do not need to set this parameter unless its default value (3) is changed. Changing the setting results in an open data connection closed and a session re-negotiation. Once this happen, you need to re-open the connection.)
- 2. C.S0033 specifies to configure the FTAP (for Subtype 0 or 1 Physical Layer) or FETAP (for Subtype 2 Physical Layer) such that the ACK Channel is transmitted at all the slots. To do this, set the ACK Channel Bit Fixed Mode to On from Application Config (F10 under Call Parms 1 of 3).
- 3. Set \hat{I}_{or} (Cell Power) to -75 dBm/1.23 MHz.
- 4. Initialize the waveform quality + code domain measurement.
- 5. Set Slots to Measure to 2 (for subtype 0 physical layer) or 1 (for subtype 2 physical layer).
- 6. Measure waveform quality + code domain.
- 7. Select Code Domain Power (F3) to view the R-Data Δ Pilot result and R-AuxPilot Δ Pilot results available in the last column of the table of data (R-Aux Pilot is only applicable to tests 8-10). In addition, for

test 5, the power in all inactive Walsh codes can be obtained by placing a marker on the inactive walsh channel, then view the Marker power result. For tests 5, 8-10 during subtype 2 physical layer tests, the Δ Pilot power of individual walsh channels constituting the R-Data (such as I:2_{SF=4}, Q:2_{SF=4}, etc.) can be obtained by placing a marker on the walsh channel, then view the Bin Δ Pilot result following the Marker power result).

- 8. Tests 2-5: Repeat steps 6-7 with RTAP rates of 19.2, 38.4, 76.8, 153.6 kbps (for subtype 0 physical layer) or with R-Data packet size of 512, 1024, 2048, 4096 bits and termination target of 16 slots (for subtype 2 physical layer).
- 9. Tests 8-10: (only applicable to subtype 2 physical layer) Repeat steps 6-7 with R-Data packet size of 3072, 6144, 12288 bits and termination target of 16 slots. (In order for the R-Aux Pilot Channel to be active for the test, the Auxiliary Pilot Channel Min Payload accessed from the Enhanced Traffic Parameters menu (see "How Do I Change Channel Gain/Traffic Info Parameters?" for how to access) must be set to a value no greater than the current R-Data payload size. NOTE: You do not need to set this parameter unless its default value (3072 bits) is changed. Changing the setting results in an open data connection closed and a session re-negotiation. Once this happen, you need to re-open the connection.)

10.A typical measurement result for test 8 is shown below.

It is the power of I:1_{SF=2} walsh channel of R-Data relative to R-Pilot. This result should be within +/- 0.25 dB of its T2P component (11.24 dB for test 8) as defined in the C.S0033-A standard (click here for specification).



It is the power of $Q:1_{SF=2}$ walsh channel of R-Data relative to R-Pilot. This result should be within +/- 0.25 dB of its T2P component (11.24 dB for test 8) as defined in the C.S0033-A standard (click here for specification).

It is the power of Auxiliary Pilot channel relative to R-Pilot. Verify that this result should be within +/- 0.25 dB of the specification (2.25 dB for test 8) as defined in the C.S0033-A standard (click here for specification).

It is the power of R-Data relative to R-Pilot. Verify that this result should be within ± 0.25 dB of the TxT2P Gain setting (14.25 dB for test 8) s defined in the C.S0033-A standard (click here for specification).

Testing 4.3.8.4 DSC Channel Output Power

- Set up an RETAP session (for Subtype 2 Physical Layer) with the following setups and then open an RETAP connection. For detailed procedure on how to open an RETAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72. (NOTE: It is recommended set the parameters prior to opening the session and connection because some of these settings are configured during session negotiation state)
 - Set the R-Data Pkt Size $(F12 \mbox{ on Call Parms 1 of 3}) \mbox{ to } 256 \mbox{ bits.}$
 - Set the Reverse Data Transmission Mode under the Application Config (F10 on Call Parms

- 1 of 3) menu to High Capacity.
- From the Power Parameters Info menu (see "How Do I Change Channel Gain/Traffic Info Parameters?" on page 88 for how to access), set the 256-bit High Capacity Termination Target to 3 (4 sub-frames, resulting in 16 slots).
- 2. C.S0033 specifies to configure the FETAP such that the ACK Channel is transmitted at all the slots. To do this, set the ACK Channel Bit Fixed Mode to On from Application Config (F10 under Call Parms 1 of 3).
- 3. Set \hat{I}_{or} (Cell Power) to -75 dBm/1.23 MHz.
- 4. Initialize the waveform quality + code domain measurement. Set Slots to Measure to 2.
- 5. Set DSC Channel Gain to -9 dB.
- 6. Measure waveform quality + code domain.
- 7. Select Code Domain Power (F3) to view the R-DSC Δ Pilot result (available in the last column of the table of data).
- 8. Set DSC Channel Gain to -12 dB and repeat steps 6-7.
- 9. A typical measurement result is shown below.

r Channel ·	— Walsh	- SF		Total CDP-	— Norm Total	- A Pilot 7
R-Pilot	I: 0	16	-11.23	-8.22	-8.22	0.00
R-AuxPil	ot					
R-BRI	I:4	16	-17.27	-14.26	-14.26	-6.04
R-DSC	I:12	32	-20.30	-20.30	-5.15	3.06
R-DRC	Q:8	16	-8.34	-5.33	-5.33	2.89
R-ACK	I:12	32	-8.17	-8.17	-5.15	3.06
R-DATA	Q:2	4	-13.58	-4.55	-4.55	3.67

Verify that this result should be within +/-0.25 dB of the DSC Channel Gain setting.

Measuring TX Spurious Emissions

- "General Procedure"
- "Testing 4.4.1 Conducted Spurious Emissions"

General Procedure

NOTE Channel power calibration should be performed if the test set is being used for the first time or the operating environment has changed significantly since the last calibration was performed. The channel power calibration also calibrates the TX spurious emissions measurement.

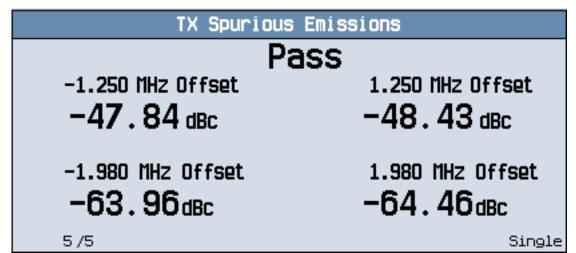
- 1. Connect the access terminal to the test set's front panel RF IN/OUT connector and power it on.
- 2. Wait for the access terminal to open a session and then open an RTAP (for subtype 0 physical layer) or RETAP (for subtype 2 physical layer) data connection for AT's transmitter test.
- 3. Set the RTAP Rate (F12) and FTAP Rate (F11) on the Call Parms 1 of 3 menu as needed if during an RTAP connection, or set the R-Data Pkt Size (F12) and F-Traffic Format (F11) on the Call Parms 1 of 3 menu as needed if during an RETAP connection.
- 4. Initialize the TX spurious emissions measurement:
 - Press the **Measurement selection** key.
 - Turn the knob to highlight the TX Spurious Emissions measurement and press the knob.
- 5. Select TX Spurious Emissions Setup (F1) to access the TX Spurious Emissions Setup menu. From this menu you can configure measurement parameters such as Mask Control and Adjacent Limit and Alternate Limit. (These parameters are only available when Mask Control is set to Manual.) For statistical measurement results, highlight the Multi-Measurement Count parameter and press the ON key. The number of averages will default to 10. You can change the value as desired.

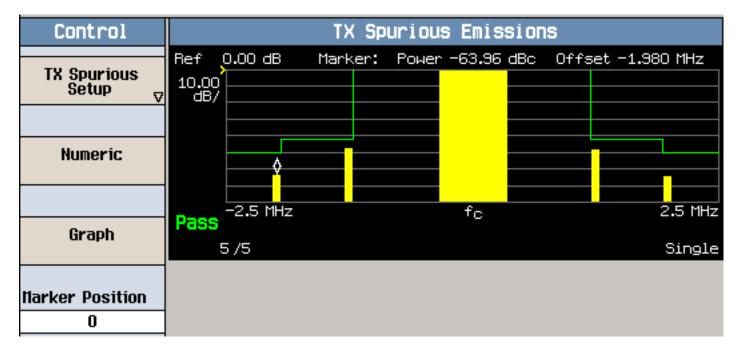
TX Spurious Emissions Setup	Value
Multi-Neasurement Count	5
Open Loop Adjust	81 dB
flask Control	Auto
Adjacent Limit	-42.00 dB
Alternate Limit	-50.00 dB
Trigger Arm	Single
Neasurement Timeout	5.0 s

6. Select Close Menu (F6) to close the TX Spurious Emissions Setup window.

- 7. From the Call Parms menu, configure Cell Power (F7), as needed.
- 8. Measure TX spurious emissions:
 - If the Trigger Arm field is set to Single, press the START SINGLE key to trigger each measurement.
 - If the Trigger Arm field is set to Continuous, the measurement began executing as soon as you initialized it in step 3.
- 9. Select Graph (F3) to display a graphical view of the results, or Numeric (F2) to display numeric results.
- 10.When viewing the graphical display, you can select Marker Position (F4) and turn the knob to display the spurious emissions levels at each of the frequency offsets.

Typical numeric and graphical measurement results are shown below:





Testing 4.4.1 Conducted Spurious Emissions

For details on performing the steps below, see the "General Procedure" on page 48 above.

- 1. Initialize the TX spurious emissions measurement.
- 2. Set the following access parameters (see "How Do I Change Access Parameters?" on page 85):
 - Set Open Loop Adjust to 81 dB or 84 dB, depending upon band class.
 - Set Probe Initial Adjust to $15 \ \mathrm{dB}$.
 - Set Probe Power Step to 7.5 dB/step.
- 3. For Subtype 0 or 1 Physical Layer, set up a Test Application session and open an RTAP connection with the RTAP Rate (F12 on the Call Parms 1 of 3 menu) set to 153.6 kbps. For detailed procedure on how to open an RTAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72.

For Subtype 2 Physical Layer, set up a Test Application session and open an RETAP connection with the following setups. For detailed procedure on how to open an RETAP session and connection, see "How Do I Open a Session and Test Data Connection?" on page 72.

- Set the R-Data Pkt Size (F12 on Call Parms 1 of 3) to 4096 bits.
- Set the Reverse Data Transmission Mode under the Application Config (F10 on Call Parms 1 of 3) menu to High Capacity.
- From the Power Parameters Info menu (see "How Do I Change Channel Gain/Traffic Info Parameters?" on page 88 for how to access), set the 4096-bit High Capacity Termination Target to 3 (4 sub-frames, 16 slots). (NOTE: You do not need to set these settings unless the default value (3) of these settings are changed. Changing these setting results in an open data connection closed because these settings are configured during session negotiation. Once this happen, you need to re-open the connection.)
- 4. C.S0033 specifies to configure the Test Application FTAP (for Subtype 0 or 1 Physical Layer) or FETAP (for Subtype 2 Physical Layer) with a Forward Traffic Channel rate of 307.2 kbps (2-slot version) and the ACK Channel is transmitted at all the slots. To do this, set the FTAP Rate (F11 on Call Parms 1 of 3) to 307.2 (2 Slot) if during subtype 0 physical layer test or set the F-Traffic Format (F11 on Call Parms 1 of 3) to 4 (1024, 2, 128) if during subtype 2 physical layer test, and set ACK Channel Bit Fixed Mode to On from

Application Config (F10 on Call Parms 1 of 3).

- 5. Set \hat{I}_{or} (Cell Power) to -60 dBm/1.23 MHz.
- 6. Set Rvs Power Ctrl to All Up bits (F7 on the Call Parms 2 of 3 menu) to transmit continuous up power control bits.
- 7. Measure TX Spurious Emissions, and note the pass/fail result.
- 8. When you have finished testing, be sure to set the Rvs Power Ctrl back to Active bits to ensure that subsequent signalling is successful.

TX Dynamic Power Measurement Description

- "How is a TX Dynamic Power Measurement Made?"
- "TX Dynamic Power Measurement Parameters"
- "TX Dynamic Power Measurement Results"
- "TX Dynamic Power Input Signal Requirements"
- "Calibrating the TX Dynamic Power Measurement"

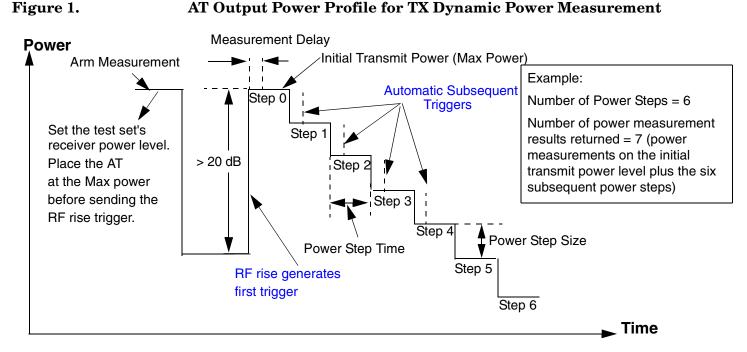
How is a TX Dynamic Power Measurement Made?

The TX dynamic power measurement provides a fast power calibration method for your AT. It is available in Active Cell and IS-856 Test operating modes.

The measurement is not performed with a call established between the test set and AT. Rather, you must place your AT into a test mode which controls the AT to transmit a power sequence of successive down steps of fixed size and duration. An example AT output power sequence for TX Dynamic Power Measurement is shown in the figure below.

Before starting the TX dynamic power measurement, you must set the test set's receiver using manual control, with the power set to match the initial transmit power of the AT's power sequence, and with the frequency set to match the AT's transmit frequency. This is required for the test set to tune its receiver properly for the initial measurement.

Typically, the dynamic power range of an AT is 90 dB, from -60dBm to +30 dBm. The TX dynamic power measurement can measure the AT's output power sequence ranging from -61 dBm to +37 dBm, in up to 99 steps. The Power Step Time may be 20, 40 or 80 ms in duration.



The TX dynamic power measurement is firstly triggered by an RF rise impulse from the AT (a positive change in power from 20 dB below the initial transmit power). To ensure successful triggering, it is recommended that you first command the AT to transmit continuously at the initial transmit power level, initiate the measurement, then command the AT to drop and then raise its output power by more than 20 dB to create the RF rise trigger.

Once triggered, the TX dynamic power measurement performs a series of channel power measurements in Very Fast speed one at each step of the power sequence. The AT's initial transmit power (step 0) is measured at 6 ms, or 16 ms, or 36 ms (corresponding to the Power Step Time set to 20ms, 40ms or 80ms) after receiving the RF rise trigger. This is to ensure that the measurements always sample the stable portions of the data record. The test set then tunes its receiver to the proper level before performing each subsequent channel power measurement based on the measured power of the prior step and the Power Step Size setting. Each

TX Dynamic Power Measurement Description

subsequent channel power measurement is automatically triggered at every 20, 40, or 80 ms (depending on the Power Step Time setting). The AT must step its power down and then hold its power constant at each step for Power Step Time duration. After completing the measurements at all of the requested power steps the test set returns power results for the initial AT transmit power (step 0) and each of the down steps.

So, the general procedure for making a TX dynamic power measurement is:

- 1. Set the test set's receiver in manual control with the power set to match the initial transmit power of the AT's power sequence, and with the frequency set to match the AT's transmit frequency.
- 2. Set the Power Step Size, Number Of Power Steps and Power Step Time parameters to match the power sequence to be transmitted by the AT.
- 3. Place your AT into the test mode required for performing TX dynamic power and command it to transmit continuously at the initial transmit power level (for example, the maximum power).
- 4. Arm the TX Dynamic Power measurement by the INIT command or by pressing the START SINGLE key.
- 5. Using the AT test mode interface, command the AT to generate an RF rise impulse (with a positive change in power from 20 dB below the initial transmit power) to trigger the measurement, and then transmit a power sequence of successive down steps of expected size and duration.
- 6. The test set measures the AT's initial transmit power and all of the requested power steps, then displays the measurement results in graphical "Bars" and numeric values.

Operating Considerations

- The TX dynamic power measurement is re-ranged and re-triggered for every step in the AT's power sequence. To prevent from missing an internal trigger at each step of a power sequence measurement, it is recommended that you do not send any GPIB commands to the test set or press any front panel keys until the measurement has completed. If the measurement misses a trigger, it aborts and returns Integrity Indicator 30: Missed Trigger
- The dynamic power measurement is not available in a multi-measurement mode.
- The TX dynamic power measurement is expected to only be used when data connection status is Idle as the AT must be operating in a test mode to transmit the required power sequence.
- The TX dynamic power measurement does not run concurrently with any other measurements. If any measurements are running when TX dynamic power measurement is initiated, they are closed and a message is displayed to indicate that they were closed. Likewise, if any other measurements are initiated while a TX dynamic power measurement is running, the TX dynamic power measurement is closed and a message is displayed.

TX Dynamic Power Measurement Parameters

• Power Step Size

Sets the power change (in dB) that the test set expects the AT to decrease between power steps. The test set re-ranges its receiver for each step power measurement based on the measured power of the prior step and this setting.

GPIB command: SETup:CTDPower:STEP[:LEVel]

• Number of Power Steps

Sets the number of power steps (steps down since its initial transmit power) that the test set expects the AT

TX Dynamic Power Measurement Description

to transmit. The total number of power results returned will be the number of this setting plus one and can be queried using the FETCh:CTDPower:COUNt[:STEP]?.

GPIB command: SETup:CTDPower:STEP:COUNt

• Power Step Time

Sets the duration (20, 40 or 80 ms) of each power measurement. The test set expects the AT to hold its power constant during each power step. The test set triggers each channel power measurement relative to the first RF rise trigger based on this setting.

GPIB command: SETup:CTDPower:STEP:TIME

• Measurement Timeout. Ensure that you set the Measurement Timeout to a value great enough to allow you to command the AT to transmit its power sequence and for the test set to measure the power sequence.

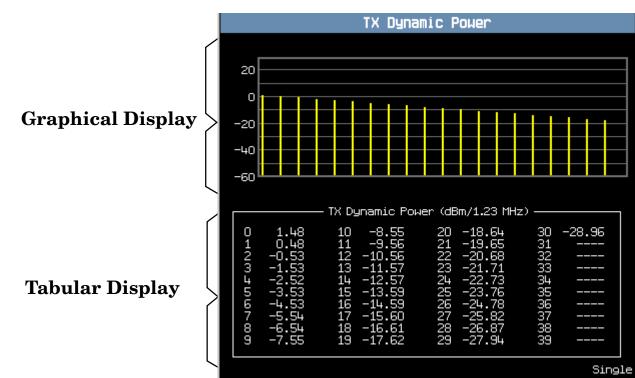
TX Dynamic Power Measurement Results

• Integrity Indicator.

Figure 2.

• Power Results - Power (dBm/1.23 MHz) are returned for the AT's initial transmit power (step 0) and each down step of the AT's transmit power sequence. The total number of power results returned is 1 + "Number of Power Steps" and can be queried using the FETCh:CTDPower:COUNt[:STEP]? command.

The TX dynamic power measurement result is displayed in both a tabular and a bar graph format. .



TX Dynamic Power Measurement Display

Graphical Display

The graphical display shows the measurement result for each step with a graphical "Bar". The x-axis graph represents the number of the power steps and y-axis represents the absolute power of the measurement step in units of dBm/1.23 MH. Up to 100 steps of the measurement results can be displayed on the graph. The view window can be adjusted to include a view of the entire 100 power step range, or reduced to include only the measurement steps of particular interest by the Graph Control softkeys.

- **NOTE** The number of displayed bars equals the value of Number of Power Steps plus one. For example, when Number of Power Steps is set to 3, the display shows 4 yellow bars in one measurement.
- Marker (F1) sets a marker position across the current span of the graph. The measurement result that corresponds with the marker position is highlighted in the table below the graphical display. This setting

TX Dynamic Power Measurement Description

also controls the table scrolling.

- Start Step (F3) sets the first measurement step displayed on the graph. It is used to adjust the view window together with the Span (F4).
- Span (F4) sets the number of measurement steps displayed on the graph. It is used to adjust the view window together with the Start Step (F3).
- Default Scale (F5) sets the Graph Marker, Start Step, and Span to their default values.

Tabular Display

A table below the graphical display lists the absolute power of each step measurement in units of dBm/1.23 MHz. The table has the capacity to display 40 steps of measurement results. To scroll through the table adjust the setting in Marker field.

TX Dynamic Power Input Signal Requirements

Input Signal Requirements

Calibrating the TX Dynamic Power Measurement

The TX dynamic power measurement is automatically calibrated during a channel power calibration. Follow the channel power calibration schedule and the TX dynamic power measurement will be properly calibrated.

This section is only applicable to the lab application and to a test application with the required feature license.

- "How is a Fast Device Tune Measurement Made?"
- "Fast Device Tune Measurement Parameters"
 - "Configuring the MS TX Frequency/Power Series"
 - "Configuring the MS RX Frequency/Power Series"
 - "Triggering the Fast Device Tune Measurement"
 - "Required Initial Conditions"
- "Fast Device Tune Measurement Results"
- "Fast Device Tune Input Signal Requirements"
- "Calibrating the Fast Device Tune Measurement"

How is a Fast Device Tune Measurement Made?

The Fast Device Tune measurement allows you to simultaneously calibrate your mobile station's transmitter (TX) output power and receiver (RX) input level across level and frequency in a single sweep (per frequency band range). The measurement is not performed with a call established between the test set and mobile station (MS). Rather, you must place your MS into a test mode which forces it to transmit a predefined series of power steps at various frequencies, and forces it to simultaneously tune its receiver to perform measurements of the test set's signal (to determine RSSI, for example) at various frequencies and power levels.

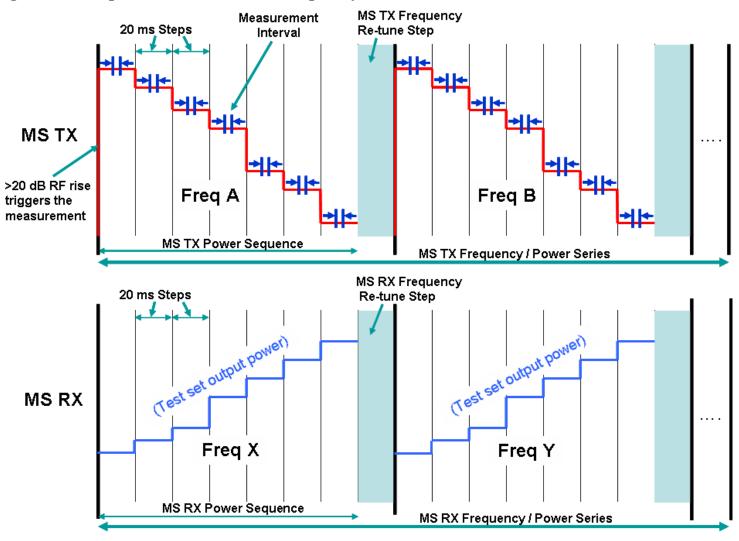


Figure 3. Example MS TX and MS RX Frequency/Power Series for Fast Device Tune Measurement

Before initiating the measurement, you must specify the power sequence that the MS will transmit (MS TX Power Sequence), and the frequencies at which the MS will transmit the power sequence (MS TX Frequency Sequence). You must also specify the power sequence you want the test set to transmit (MS RX Power Sequence), and the frequencies at which you want the test set to transmit the power sequence (MS RX Frequency Sequence).

Configuring the MS TX Frequency/Power Series

The MS TX Power Sequence may include up to 20 steps (of 20 ms duration) that span some or all of the measurement's input range (the levels can step up or down with varying magnitudes of change, as long as the first step in the sequence provides a 20 dB rise to trigger the measurement). The MS TX Frequency Sequence may include up to 20 frequencies (within one frequency band range).

The test set can measure a total of 400 power points in one measurement cycle (20 power values at 20 different frequencies). However, the measurement allows you to enter up to 40 "MS TX Power Step Levels" and 40 "MS TX Frequency Step Values" (indexed from 0 to 39). You must then use the "MS TX Power Step Start Index" and "Number of Power Steps" settings to specify which power steps comprise the MS TX Power Sequence, and

the "MS TX Frequency Step Start Index" and "Number of Frequency Steps" settings to specify which frequency steps comprise the MS TX Frequency Sequence. See "Frequency/Power Series Example" on page 60 for an example illustrating how to utilize this flexibility.

The test set uses the values in the MS TX Power Sequence and the MS TX Frequency Sequence to build the MS TX Frequency/Power Series, which drives how the test set's receiver is tuned throughout the measurement cycle. To build the MS TX Frequency/Power Series, the test set simply repeats the MS TX Power Sequence at each of the frequencies in the MS TX Frequency Sequence, and inserts a frequency re-tune step in between each repetition of the power sequence (to allow the test set and MS to re-tune to the new frequency; no measurements are performed by the test set during the frequency re-tune steps). During the frequency re-tune steps, the test set tunes its receiver to the power and frequency values required for the first step in the next power sequence. The frequency re-tune steps are the same step length as the power sequence steps (20 ms).

Before initiating the measurement, you must ensure that your MS is set to transmit the MS TX Frequency/Power Series you've set in the test set, including the frequency re-tune steps.

Configuring the MS RX Frequency/Power Series

While the test set is measuring the MS TX Power Sequence, it also transmits a MS RX Power Sequence for the MS to measure. This MS RX Power Sequence must include the same number of power steps as the MS TX Power Sequence (up to 20 steps of 20 ms duration). These steps can be at any power level in the test set's Cell Power output range.

The test set transmits its MS RX Power Sequence at each of the frequencies in the MS RX Frequency Sequence. The MS RX Frequency Sequence may include up to 20 frequencies within one frequency band range (which does not have to be the same frequency band range as the MS TX Frequency Sequence). The number of frequencies in the MS RX Frequency Sequence must match the number of frequency steps in the MS TX Frequency Sequence.

If you do not want the MS to measure test set power at as many power levels or frequencies as you want the test set to measure from the MS, simply place "dummy" power levels or frequencies at the end of the MS RX Power Sequence and MS RX Frequency Sequence (for example, simply repeat the final power level or frequency). You can then ignore the mobile station's measurement results for these "dummy" points. Likewise, if you need more measurement points in the MS RX Frequency/Power Series than in the MS TX Frequency/Power Series, you can place "dummy" power levels and frequencies in the MS TX Frequency/Power Series, but note that the test set will still measure and report power for these "dummy" points. You must simply ignore these results.

As with the MS TX Frequency/Power Series, the test set can transmit a total of 400 power points in one measurement cycle (20 power values at 20 different frequencies), but the measurement allows you to enter up to 40 "MS RX Power Step Levels" and 40 "MS RX Frequency Step Values" (indexed from 0 to 39). You must then use the "MS RX Power Step Start Index" and "Number of Power Steps" settings to specify which power steps comprise the MS RX Power Sequence, and the "MS RX Frequency Step Start Index" and "Number of Frequency Steps" settings to specify which frequency steps comprise the MS RX Frequency Sequence. See "Frequency/Power Series Example" on page 60 for an example illustrating how to utilize this flexibility.

As with the MS TX Frequency/Power Series, the test set uses the values in the MS RX Power Sequence and the MS RX Frequency Sequence to build the MS RX Frequency/Power Series, which drives how the test set's generator is tuned throughout the measurement cycle. To build the MS RX Frequency/Power Series, the test set simply repeats the MS RX Power Sequence at each of the frequencies in the MS RX Frequency Sequence, and inserts a frequency re-tune step in between each repetition of the power sequence (to allow the test set and MS to re-tune to the new frequency; the MS should not perform any measurements on the test set's signal during this time, or if a measurement is performed, you should ignore the measurement results). During the

frequency re-tune steps, the test set moves its generator to the power and frequency values required for the first step in the next power sequence. The frequency re-tune steps are the same step length as the power sequence steps (20 ms).

Before initiating the measurement, you must ensure that your MS is set to measure the MS RX Frequency/Power Series you've set in the test set, and that its tuning profile includes the frequency re-tune steps. Your mobile station should be configured to measure the test set's signal 5 ms after the start of each step, to allow the test set's source to settle.

Frequency/Power Series Example

The test set can measure/transmit 400 power points in one measurement cycle (20 power values at 20 different frequencies). However, you can enter up to 40 power values and 40 frequencies for both the MS TX and MS RX sequences. This flexibility is present to make it more efficient for you to test different power sequences over different sets of frequencies or, more commonly, to test the same power sequence over different bands. You must load in the superset of power levels and frequency values once. Then for each measurement cycle, you simply change the start index and number of steps as needed and initiate the measurement.

For example, to measure a MS TX sequence of 14 power step levels in both the US Cellular and US PCS frequency bands:

- MS transmit power levels (dBm): 20, 16, 12, 8, 4, 0, -4, -8, -12, -16, -20, -30, -40, -50
- US Cellular band, frequencies (MHz): 826.2, 829.2, 835.2, 838.2, 841.2, 847.2
- US PCS band, frequencies (MHz): 1852.5, 1856.5, 1860.5, 1864.5, 1870.5, 1874.5, 1878.5, 1882.5, 1886.5, 1890.5, 1894.5, 1898.5, 1902.5

and to transmit a MS RX sequence of 8 power step levels for the mobile station to measure:

- Test set transmit power levels (dBm): -90, -80, -70, -60, -50, -40, -30, -20
- US Cellular band, frequencies (MHz): 871.2, 874.2, 880.2, 883.2, 886.2, 892.2
- US PCS band, frequencies (MHz): 1932.5, 1936.5, 1940.5, 1944.5 1950.5, 1954.5, 1958.5, 1962.5, 1966.5, 1970.5, 1974.5, 1978.5, 1982.5

for multiple US Cellular/US PCS mobile stations, set the following:

- MS TX Power Step Levels = 20, 16, 12, 8, 4, 0,-4, -8, -12, -16, -20, -30, -40, -50
 MS RX Power Step Levels = -90, -80, -70, -60, -50, -40, -30, -20, -75, -75, -75, -75, -75 (note that the
 last six values "-75" are "dummy" values required so that there are an equal number of power steps in the
 MS TX and MS RX sequences)
 MS TX Frequency Step Values = 826.2, 829.2, 835.2, 838.2, 841.2, 847.2, 1852.5, 1856.5, 1860.5,
 1864.5, 1870.5, 1874.5, 1878.5, 1882.5, 1886.5, 1890.5, 1894.5, 1898.5, 1902.5
 MS RX Frequency Step Values = 871.2, 874.2, 880.2, 883.2, 886.2, 892.2, 1932.5, 1936.5, 1940.5, 1944.5
 1950.5, 1954.5, 1958.5, 1962.5, 1966.5, 1970.5, 1974.5, 1978.5, 1982.5
- 2. MS TX Power Step Start Index = 0 MS RX Power Step Start Index = 0 Number of Power Steps = 14
- 3. Mobile station #1:
 - MS TX Frequency Step Start Index = 0 MS RX Frequency Step Start Index = 0

Number of Frequency Steps = 6 Initiate the measurement, query INITiate:CFDTune:ARMed?, fetch the results

- MS TX Frequency Step Start Index = 6 MS RX Frequency Step Start Index = 6 Number of Frequency Steps = 13 Initiate the measurement, query INITiate:CFDTune:ARMed?, fetch the results
- 4. Mobile station #2: repeat step 3
- 5. Mobile station #3: repeat step 3

6. ...

Triggering the Fast Device Tune Measurement

The MS must trigger the measurement with a positive change in power of at least 20 dB (the mobile station's power must rise from 20 dB below the level of the first step in the MS TX Power Sequence to within 9 dB of the level of the first step).

To ensure successful triggering, it is recommended that you do the following:

1. Order the MS to transmit continuously at >20 dB below the power level of the first step in the MS TX Power Sequence.

Note: If your MS TX Power Sequence starts at a power level that is less than 20 dB above the minimum transmit power of your MS, then you must include a trigger pulse as the first step in the MS TX Power Sequence. The power level of this trigger pulse will be measured by the test set as one of the steps in the sequence.

- 2. Initiate the Fast Device Tune measurement (this prepares the test set's hardware to execute the frequency/power series you've specified and arms the measurement's RF rise trigger).
- 3. Send the INITiate:CFDTune:ARMed? query and wait for it to return a value of 1, indicating that the measurement is armed and ready to be triggered (or wait ~2 seconds if running the measurement from the front panel).
- 4. Order the MS to begin transmission of its MS TX Frequency/Power Series (the MS should then increase its output power by more than 20 dB to reach the first step in the series, which triggers the measurement with an RF rise).

Once triggered, the Fast Device Tune measurement performs a series of channel power measurements, one near the center of each step of the MS TX Power Sequence (while simultaneously transmitting the MS RX Power Sequence you've specified), then repeats the measurements at the next specified MS TX frequency (while simultaneously transmitting the MS RX Power Sequence at the next specified MS RX frequency). The test set tunes its receiver for each step according to the power levels you've specified for the MS TX Power Sequence. The MS must step its power according to the MS TX Power Sequence (and be within +/- 9 dB of the expected power level for each step) and hold its power constant for the duration of the measurement interval (312.5 us, 7 ms after the start of each step). After completing a measurement at each step of the MS TX Frequency/Power Series, the measurement returns power results for all of the measured steps.

Required Initial Conditions

- Operating Mode must be set to IS-856 Test.
- Rcvr Power Ctrl must be set to Manual and Meas Frequency must be set to manual control. To set Meas Frequency to manual control from the front panel, press the OFF/MANUAL key. This sets Meas

Frequency to the last frequency value that this parameter was set to. The Fast Device Tune measurement ignores the specific value that Meas Frequency is set to, so it can be set to any supported input frequency; the measurement simply requires that Meas Frequency be in manual control mode

- RF Gen Freq Ctrl must be set to Manual.
- AWGN Power must be Off. If in the Lab Application, also make sure no external fading is applied.
- The Fast Device Tune measurement is only supported on the **RF IN/OUT** port. If your test set includes an **RF OUT ONLY** port, RF Output Port (**F6** on the System Config screen) must be set to **RF IN/OUT**.
- You must configure the MS TX Frequency/Power Series to match the pattern of power levels to be transmitted by the MS and configure the MS RX Frequency/Power Series to match the pattern of power levels to be measured by the MS.

Operating Considerations

The Fast Device Tune measurement must re-range and re-trigger for every step in the MS TX Power Sequence. To ensure that this process is not interrupted by other operations, it is recommended that you not send any GPIB commands to the test set or press any front panel keys until the measurement has completed. If the measurement misses a trigger, it aborts and returns Integrity Indicator 30: Missed Trigger.

No other measurements can be running when a Fast Device Tune measurement is performed. If any measurements are running when a Fast Device Tune measurement is initiated, they are closed and a message is displayed to indicate that they were closed. Likewise, if any other measurements are initiated while a Fast Device Tune measurement is running, the Fast Device Tune measurement is closed and a message is displayed.

 $Measurement\ results\ (and\ the\ RF\ generator\ output\ level)\ are\ affected\ by\ any\ {\tt RF\ IN/OUT\ Amplitude\ Offsets\ that\ are\ entered.}$

Fast Device Tune Measurement Parameters

Fast Device Tune Setup

• Measurement Timeout

Ensure that you set the Measurement Timeout to a value great enough to allow you to command the MS to transmit its MS TX Frequency/Power Series and for the test set to measure the MS TX Frequency/Power Series. For example, measuring the maximum allowable number of 400 power points can take more than 10 seconds (400 steps plus the 19 re-tune steps: $419 \times 20 \text{ ms} = 8.4 \text{ seconds}$, plus ~ 2 seconds required for the measurement to prepare for triggering).

GPIB command: SETup:CDFTune:TIMeout[:STIMe]

• MS TX Power Step Start Index

Indicates which of the MS TX Power Step Levels is the first step in the MS TX Power Sequence.

This parameter can be set to any integer value between 0 and 39. However, MS TX Power Step Start Index + Number of Power Steps" must not exceed 40.

Also, you must ensure that the range of values selected by MS TX Power Step Start Index and Number of Power Steps do not include any NANs (9.91E+37) or values that are outside of the input range for the current application format (considering the amplitude offset settings).

GPIB command: SETup:CDFTune:MS:TX:POWer:STEP:STARt:[INDex]

• MS TX Frequency Step Start Index

Indicates which of the MS TX Frequency Step Values is the first frequency in the MS TX Frequency Sequence.

This parameter can be set to any integer value between 0 and 39. However, MS TX Frequency Step Start Index + Number of Frequency Steps must not exceed 40.

Also, the frequencies indicated by MS TX Frequency Step Start Index and Number of Frequency Steps must be within one frequency band range (and must not include any NANs (9.91E+37)).

GPIB command: SETup:CDFTune:MS:TX:FREQuency:STEP:STARt:[INDex]

• MS RX Power Step Start Index

Indicates which of the MS RX Power Step Levels is the first step in the MS RX Power Sequence.

This parameter can be set to any integer value between 0 and 39. However, MS RX Power Step Start Index + Number of Power Steps must not exceed 40.

Also, you must ensure that the range of values selected by MS RX Power Step Start Index and Number of Power Steps do not include any NANs (9.91E+37) or values that are outside of the output range for the current application format (considering the amplitude offset settings).

GPIB command: SETup:CDFTune:MS:RX:POWer:STEP:STARt:[INDex]

• MS RX Frequency Step Start Index

Indicates which of the MS RX Frequency Step Values is the first frequency in the MS RX Frequency Sequence.

This parameter can be set to any integer value between 0 and 39. However, MS RX Frequency Step Start Index + Number of Frequency Steps must not exceed 40.

Also, the frequencies indicated by MS RX Frequency Step Start Index and Number of Frequency Steps must be within one frequency band range (and must not include any NANs (9.91E+37)).

GPIB command: SETup:CDFTune:MS:RX:FREQuency:STEP:STARt:[INDex]

• Number of Power Steps

Indicates how many (consecutive) MS TX Power Step Levels are used for the MS TX Power Sequence, and how many (consecutive) MS RX Power Step Levels are used for the MS RX Power Sequence.

This parameter can be set to any integer value between 1 and 20, but MS TX Power Step Start Index + Number of Power Steps and MS RX Power Step Start Index + Number of Power Steps must not exceed 40.

Also, you must ensure that the range of power values selected by MS TX Power Step Start Index, MS RX Power Step Start Index and Number of Power Steps do not include any NANs (9.91E+37) or values that are outside of the input or output ranges for the current application format (considering the amplitude offset settings).

GPIB command: SETup:CDFTune:POWer:STEP:COUNt

• Number of Frequency Steps

Indicates how many (consecutive) MS TX Frequency Step Values are used for the MS TX Frequency Sequence, and how many (consecutive) MS RX Frequency Step Values are used for the MS RX Frequency

Sequence.

This parameter can be set to any integer value between 1 and 20, but MS TX Frequency Step Start Index + Number of Frequency Steps and MS RX Frequency Step Start Index + Number of Frequency Steps must not exceed 40.

Note that the frequencies indicated by MS TX Frequency Step Start Index and Number of Frequency Steps must be within one frequency band range. Likewise, the frequencies indicated by MS RX Frequency Step Start Index and Number of Frequency Steps must be within one frequency band range, but do not have to be in the same frequency band range as the MS TX Frequency Sequence. Ensure that none of the frequency values you've selected are NANs (9.91E+37)).

GPIB command: SETup:CDFTune:FREQuency:STEP:COUNt

Fast Device Tune MS TX/RX Parameters

• MS TX Power Step Levels

You can specify up to 40 mobile station output power levels (indexed from 0 up to 39). You must use the MS TX Power Step Start Index" and Number of Power Steps settings to specify which of these (consecutive) power levels (up to 20) are used for the MS TX Power Sequence.

Although you can enter any power levels between -129 and +80 dBm (because this measurement is common to the W-CDMA/HSDPA, 1xEV-DO and cdma2000 formats), when running the Fast Device Tune measurement in the 1xEV-DO application/format, you can only measure power levels in the range of -79 to +30 dBm and the measurement is only specified for power levels in the range of -61 to +30 dBm (these ranges assume an amplitude offset of 0; the ranges change as you change amplitude offsets.)

GPIB command: SETup:CDFTune:MS:TX:POWer:STEP[:LEVels]

• MS TX Frequency Step Values

You can specify up to 40 mobile station uplink frequencies (indexed from 0 up to 39). You must use the "MS TX Frequency Step Start Index" and Number of Frequency Steps settings to specify which of these (consecutive) frequencies (up to 20) are used for the MS TX Frequency Sequence.

Although you can enter any frequencies between 411 and 1980 MHz, when running the Fast Device Tune measurement in the 1xEV-DO application/format, you can only test frequencies within a single 1xEV-DO frequency band range:

- 411 to 479 MHz (Band: NMT-450)
- 806 to 924 MHz (Bands: US Cellular, Japan CDMA, China Cellular, and Secondary 800)
- 1750 to 1780 MHz (Band: Korean PCS)
- 1920 to 1980 MHz (Band: IMT-2000)
- 1850 to 1915 (Bands: US PCS and US PCS 1900)

GPIB command: SETup:CDFTune:MS:TX:FREQuency:STEP[:VALues]

• MS RX Power Step Levels

You can specify up to 40 test set output power levels (indexed from 0 up to 39). You must use the MS RX Power Step Start Index and Number of Power Steps settings to specify which of these (consecutive) power levels (up to 20) are used for the MS RX Power Sequence.

Although you can enter any power levels between -165 and 37 dBm, when running the Fast Device Tune

measurement in the 1xEV-DO application/format, the test set can only transmit test power levels in the range of -120 to -13 dBm (this range assumes an amplitude offset of 0; the allowable range changes as you change amplitude offsets.)

GPIB command: SETup:CDFTune:MS:RX:POWer:STEP[:LEVels]

• MS RX Frequency Step Values

You can specify up to 40 test set downlink frequencies (indexed from 0 up to 39). You must use the MS RX Frequency Step Start Index and Number of Frequency Steps settings to specify which of these (consecutive) frequencies (up to 20) are used for the MS RX Frequency Sequence.

Although you can enter any frequencies between 421 and 2170 MHz, when running the Fast Device Tune measurement in the 1xEV-DO application/format, you can only test frequencies within a single 1xEV-DO frequency band range:

- 421 to 489 MHz (Band: NMT-450)
- 800 to 960 MHz (Bands: US Cellular, Japan CDMA, China Cellular, and Secondary 800)
- 1840 to 1870 MHz (Band: Korean PCS)
- 2110 to 2170 MHz (Band: IMT-2000)
- 1930 to 1995 (Bands: US PCS and US PCS 1900)

GPIB command: SETup:CDFTune:MS:RX:FREQuency:STEP[:VALues]

Fast Device Tune Measurement Results

The Fast Device Tune measurement results are currently only available via GPIB command. Measurement results are not available on the front panel screen.

- Integrity Indicator
- Power

The test set performs a channel power measurement near the center of each step (7 ms after the start of the step), with a measurement interval of 312.5 us (1/4 timeslot). Power (dBm/1.23 MHz) is returned for each step in the MS TX Frequency/Power Series (except for the frequency re-tune steps). The total number of results returned by the measurement is always 400 (Number of Power Steps x Number of Frequency Steps power result values are returned, followed by 9.91E+37 (NAN) for all remaining values up to 400). The power results for the first frequency in the MS TX Frequency Sequence are returned first, then the power results for the second frequency in the MS TX Frequency Sequence, etc., followed by NANs if fewer than 400 points were measured.

Note that the test set does not report the mobile station's measurement results (for example, RSSI). You must capture the mobile station's measurement results so that you can compare its measurements with the test set's actual transmission levels.

Fast Device Tune Input Signal Requirements

The Fast Device Tune measurement meets specifications when the following input signal requirements are met:

• Frequency: 411 to 420 MHz, 450 to 484 MHz, 824 to 934 MHz, 1750 to 1780 MHz, 1850 to 1980 MHz

- Input level: -61 dBm to +30 dBm (the measurement can accept power within the range of -79 dBm to +30 dBm)

Calibrating the Fast Device Tune Measurement

You must calibrate this measurement using the Calibrate Measurements procedure.

Appendix

This Appendix includes some general setup procedures that are required to perform the tests, and other helpful information:

- "Test Adherence to Standards" on page 68
- "How Do I Open a Session and Test Data Connection?" on page 72
- "How Do I Perform a Handoff?" on page 70
- "How Do I Change Call Parameters?" on page 77
- "How Do I Change Cell Parameters?" on page 83
- "How Do I Change Access Parameters?" on page 85
- "How Do I Change Channel Gain/Traffic Info Parameters?" on page 88
- "How Do I Change Generator Information?" on page 93
- "How Do I Change Configurable Attribute Control Mode?" on page 95
- "Calibrating the Test Set" on page 97
- "Amplitude Offset" on page 105

Test Adherence to Standards

Standards Table

Unless otherwise indicated, the capabilities shown in the tables apply to both the E1966A and the E6706A applications.

Table 1. Support of C.S0033-A Tests

C.S0033-A Test	Supported by Test Set?	Comments
3. Receiver Tests	I	
3.1 Frequency Coverage Requirements	Yes	Supports Band Classes 0, 1, 3, 4, 5, 6, 10 and 14.
3.2.2 Demodulation of Forward Traffic Channel in Multipath Fading	Yes	See "Testing 3.2.1 Demodulation of Forward Traffic Channel in AWGN" on page 9.
3.2.2 Demodulation of Forward Traffic Channel in Multipath Fading	Yes. (Lab Applicatio n Only)	Requires external fader and AWGN generator. For example, the E5515C Fading Solution, see "Digital Bus Information" for reference information. (<i>Lab Application Only</i>)
3.2.3 Decision of Power Control Bit for Channels Belonging to Different Power Control Sets During Soft Handoff	No	Requires soft handoff capability.
3.2.4 Decision of Power Control Bit for Channels Belonging to the Same Power Control Set	No	Requires soft handoff capability.
3.2.5 Demodulation of Reverse Power Control Channel During Soft Handoff	No	Requires soft handoff capability.
3.2.6 Demodulation of ARQ Channel	No	
3.2.7 Demodulation of Broadcast Channel	No	
3.3.1 Receiver Sensitivity and Dynamic Range	Yes	See "Testing 3.3.1 Receiver Sensitivity and Dynamic Range" on page 12.
3.3.2 Single Tone Desensitization	Partially	Requires external CW signal generator.
3.3.3 Intermodulation Spurious Response Attenuation	Partially	Requires two external CW signal generators.
3.3.4 Adjacent Channel Selectivity	Partially	Requires external HRPD (1xEV-DO) and CDMA sources.
3.3.5 Receiver Blocking Characteristics	Partially	Requires external CW signal generator.
3.4.1 Conducted Spurious Emissions	No	Requires full spectrum analyzer
3.4.2 Radiated Spurious Emissions	No	Requires full spectrum analyzer

Table 1. Support of C.S0033-A Tests

C.S0033-A Test	Supported by Test Set?	Comments
4. Transmitter Tests	I	I
4.1.1 Frequency Coverage	Yes	Supports Band Classes 0, 1, 3, 4, 5, 6, 10 and 14.
4.1.2 Frequency Accuracy	Yes	See "Testing 4.2.2 Waveform Quality and Frequency Accuracy" on page 40.
4.2.1 Time Reference	Partially	Supports static time reference only.
4.2.2 Waveform Quality and Frequency Accuracy	Yes	See "Testing 4.2.2 Waveform Quality and Frequency Accuracy" on page 40.
4.3.1 Range of Open Loop Output Power	Partially	Supports 100% forward packet activity only.
		If you want to view the access probe sequence graphically, use "Measuring Graphical Access Probe Power" on page 17 (<i>Lab Application Only</i>).
4.3.2 Time Response of Open Loop Power Control	Yes	See "Testing 4.3.2 Time Response of Open Loop Power Control" on page 26
4.3.3 Range of Closed Loop Power Control	Partially	Supports tests 1 and 3-11, Minimum Standard (a) only, by remote program only.
3.1.2.3.4 Maximum RF Output Power	Yes	See "Testing 4.3.4 Maximum RF Output Power" on page 29
4.3.5 Minimum Controlled Output Power	Yes	See "Testing 4.3.5 Minimum Controlled Output Power" on page 32
4.3.6 Standby Output Power	Partially	Supports idle standby output power fully.
		Supports measurement of standby power between access probe bursts by remote program only.
3.1.2.3.7 RRI Channel Output Power	Yes	See "Testing 4.3.7 RRI Channel Output Power" on page 41
4.3.8.1 DRC Channel Output Power	Yes	See "Testing 4.3.8 Code Domain Power" on page 42
4.3.8.2 ACK Channel Output Power	Yes	See "Testing 4.3.8 Code Domain Power" on page 42
4.3.8.3 Data Channel Output Power	Partially	Supports tests 1-5, 8-10.
		See "Testing 4.3.8 Code Domain Power" on page 42
4.3.8.4 DSC Channel Output Power	Yes	This test is only used for subtype 2 physical layer testing. See "Testing 4.3.8 Code Domain Power" on page 42
4.4.1 Conducted Spurious Emissions	Yes	Supports adjacent and alternate channels only.
		"Testing 4.4.1 Conducted Spurious Emissions" on page 50
4.4.2 Radiated Spurious Emissions	Partially	Requires external spectrum analyzer.
4.4.3 Occupied Bandwidth	Partially	Requires external spectrum analyzer.

How Do I Perform a Handoff?

1. Press the CALL SETUP key.

	Call Setup Screen	
Call Control	Active Cell Operating Mode	Call Parms
Operating Node	Access Terminal Information (AT Reported)	Cell Pouer
Active Cell	Session Seed: 0x6D5B927A	-55.00
	Harduare ID Type (Hex): 0x010000 ESN	dBm/1.23 MHz
	Harduare ID (Hex): 0x7403BA66	Cell Band
	Harduare ID (Decimal): 116-00244326	US PCS
	Access Terminal Information (AN Assigned)	Channel
End Data	UATI 024: 1	500
Connection	UATI Color Code: 64	
	MAC Index: 5	
Close Session	Access Terminal Information (User Entered)	Application Config _V
	AT Nax Poyer: 23 dBm/1.23 NHz	FTAP Rate
Handoff	Application Configuration	307.2 kbps
Setup _V	Application FTAP	(2 Slot, QPSK)
AT Nax Pouer	Limited TAP: Off	
23 dBm/1.23 fHz	AT Directed Packets: 50 %	RTAP Rate 9.6 kbps
23 UDIII/ 1.23 TINZ		3.0 KDPS
Ī	Active Cell Sys Type: IS-856	
	Connected	
1 of 2	IntRef Offset	TAP 1 of 3

2. Select Handoff Setup (F5).

	Call Setup Screen		
Handoff Setup	Active Cell Operating Mo	Call Parms	
	Access Terminal Information (AT Re	Cell Pouer	
	Session Seed: 0x6D5B927A	-55.00	
	Hardware ID Type (Hex): 0x010000 E		dBm/1.23 MHz
	Harduare ID (Hex): 0x7403BA66		Cell Band
	Harduare ID (Decimal): 116-002443	26	US PCS
	Access Terminal Information (AN As	signéd)	Channel
	UATI 024: 1		500
	Handoff Setup	Value	
	Handoff Cell Band	US PCS	Analiantian
	Handoff Channel	525	Application Config _⊽
Europute			FTAP Rate
Execute Handoff			307.2 kbps
			(2 Slot, QPSK)
01			RTAP Rate
Close Henu			9.6 kbps
	Active Cell	Sys Type: IS-856	
	Session Open		2
1 of 2	IntRef Offset	FTAP	1 of 3

- 3. Highlight Handoff Cell Band and select the desired band.
- 4. Highlight Handoff Channel and select the desired channel.
- 5. Select Execute Handoff (F5) to complete the handoff, or Close Menu (F6) to abort the handoff.
- 6. Check for Connected in the Active Cell field.

You can also simply change Cell Band and/or Channel from the Call Parms menu and the test set immediately negotiates the connection to the new cell band and/or channel.

How Do I Open a Session and Test Data Connection?

To allow testing of access terminal (AT) minimum performance operating at subtype 0 physical layer, an FTAP or RTAP data connection must be established between the test set and the AT. To allow testing of access terminal (AT) minimum performance operating at subtype 2 physical layer, an FETAP or RETAP data connection must be established between the test set and the AT.

A. Configure Call Parameters

- 1. Press the CALL SETUP key.
- 2. Select Operating Mode (F1) and set the operating mode to Active Cell.
- 3. Configure the parameters necessary for your access terminal to find service with the test set, such as Cell Power, Cell Band and Channel (see "How Do I Change Call Parameters?" on page 77).
- 4. If you were using the *Lab Application*, prior to opening a test application session, verify that the Session Application Type accessed from the Application Config (F10 on the Call Parms menu) is set to Test Application.
- 5. If you plan to open a TAP test data connection, configure the test set to subtype 0 physical layer. See "To Configure the Test Set to Subtype 0 Physical Layer" for detailed procedure.

If you plan to open an ETAP data connection, configure the test set to subtype 2 physical layer. See "To Configure the Test Set to Subtype 2 Physical Layer" for detailed procedure.

B. Open a Session

A session can only be established from the access terminal. The test set can not open a session.

- 1. Turn on the access terminal and wait for it to open a session.
- 2. Check for Session Open in the Active Cell status field and AT reported information displayed on the Call Setup Screen.
 - If you've set the test set to subtype 0 physical layer, a typical display after a session open is as below.

rol		Active Cell Opera	ating Mode		Call Parms
de					Cell Pouer
:11	Acce	ss Terminal Informati	on (AT Reporte	ed)	-55.00
	Session Seed	1:	0x49026E1	1	dBm/1.23 fHz
	Harduare ID	Type (Hex):	0x010000	ESN	Cell Band
	Harduare ID	(Hex):	0x741109C	F	US PCS
	Harduare ID	(Decimal):	116-01116	623	
	Acce	ss Terminal Informati	on (AN Assigne	ed)	Channel
a In	UATI 024:		1		300
<i>"</i>	UATI Color C	ode:	64		
	IAC Index:		15		
	41 1				
		Application Confi	guration		Application Config ,
	Session Appl	Application Confi ication Type:	guration Test Appli	cation	Application Config _s
				cation	Application Config , FTAP Rate
		ication Type:	Test Appli	cation	Config ,
	Test Applica	ication Type: tion Protocol:	Test Appli FTAP	cation	Config , FTAP Rate
r	Test Applica Limited TAP: AT Directed I DRC Value Fi	ication Type: tion Protocol: Packets: xed Node Attribute:	Test Appli FTAP Off 50 % On	cation	Config FTAP Rate 307.2 kbps
r I ∏Hz	Test Applica Limited TAP: AT Directed I DRC Value Fi	ication Type: tion Protocol: Packets:	Test Appli FTAP Off 50 % On	cation	Config FTAP Rate 307.2 kbps (2 Slot, QPSK)
r	Test Applica Limited TAP: AT Directed I DRC Value Fi	ication Type: tion Protocol: Packets: xed Node Attribute: Bit Fixed Node Attribu	Test Appli FTAP Off 50 % On Ite: On		Config FTAP Rate 307.2 kbps (2 Slot, QPSK) RTAP Rate
r	Test Applica Limited TAP: AT Directed I DRC Value Fi	ication Type: tion Protocol: Packets: xed Node Attribute: Bit Fixed Node Attribu	Test Appli FTAP Off 50 % On Ite: On Sys T	ype: IS-856	Config FTAP Rate 307.2 kbps (2 Slot, QPSK) RTAP Rate
r	Test Applica Limited TAP: AT Directed I DRC Value Fi	ication Type: tion Protocol: Packets: xed Node Attribute: Bit Fixed Node Attribu Active Cell Session Open	Test Appli FTAP Off 50 % On Ite: On Sys T		Config FTAP Rate 307.2 kbps (2 Slot, QPSK) RTAP Rate

How Do I Open a Session and Test Data Connection?

• If you've set the test set to subtype 2 physical layer, a typical display after a session open is as below.

		-
rol	Active Cell Operating Mode	Call Parms
de	Access Terminal Information (AT Reported)	Cell Pouer
11	Session Seed: 0x49026E11	-55.00
	Harduare ID Type (Hex): 0x010000 ESN	dBm/1.23 MHz
	Harduare ID (Hex): 0x741109CF	Cell Band
	Harduare ID (Decimal): 116-01116623	US PCS
	Access Terminal Information (AN Assigned)	
	UATI 024: 1	Channel
1 n	UATI Color Code: 64	300
	MAC Index: 15	
	Application Configuration	
	Session Application Type: Test Application	Application Config
	Enhanced Test Application Protocol: FETAP	
	AT Directed Packets: 50 %	F-Traffic Format
	DRC Value Fixed Node Attribute: On ACK Channel Bit Fixed Node Attribute: On	4 (1024,2,128)
	ACK Channel Nodulation Type: Bi-Polar Keying	(307.2k, QPSK)
.	Reverse Data Transmission Node:	R-Data Pkt Size
ПHz	Expected Enhanced Access Rate: Unknown	128
		bits
	Active Cell Sys Type: IS-856	
	Session Open Logging: No Conn.	
	DBUS-INT IntRef PLSub2 FE	TAP 1 of 3

C. Open a Test Application Connection

- 1. If you've set the test set to subtype 0 physical layer, you can open an FTAP or RTAP connection for AT's receiver and transmitter tests.:
 - Select Application Config (F10 on the Call Parms 1 of 3 menu).
 - Set Test Application Protocol to FTAP or RTAP. Select Close Menu (F6)
 - Set FTAP Rate (F11) or RTAP Rate (F12) on the Call Parms 1 of 3 menu, as needed.

If you've set the test set to subtype 2 physical layer, you can open an FETAP or RETAP connection for AT's receiver and transmitter tests.:

- Select Application Config (F10 on the Call Parms menu).
- Set Enhanced Test Application Protocol to FETAP or RETAP. Select Close Menu (F6)
- Set F-Traffic Format (F11) or R-Data Pkt Size (F12) on the Call Parms 1 of 3 menu, as needed.
- 2. Select Start Data Connection (F3 on Call Control menu) to page the access terminal.
- 3. Check for Connected in the Active Cell status field. Also, the type of test application (FTAP, RTAP, FETAP or RETAP) and physical layer subtype (PLSub0 or PLSub2) being configured for the current connection is also indicated at the right bottom of the status area. An example display after an FTAP test

data connection is shown as below.

Active Cell Ope	erating Mode
Access Terminal Inform	ation (AT Reported)
Session Seed:	0x70BE9BC0
Harduare ID Type (Hex):	0x010000 ESN
Harduare ID (Hex):	0x2321B63F
Harduare ID (Decimal):	035-02209343
Access Terminal Inform	ation (AN Assigned)
UATI 024:	5
UATI Color Code:	64
MAC Index:	5
	A: 11
Application Co	nfiguration
Session Application Type:	Test Application
Test Application Protocol:	FTAP
Limited TAP:	Off
AT Directed Packets:	50 %
DRC Value Fixed flode Attribute:	On
ACK Channel Bit Fixed flode Attr	ibute: On
Active Cell	Sys Type: IS-856
Connected	Logging: No Conn.
IntRef	PLSub0 FTAP

4. You can change the application type between FTAP and RTAP as well as the associated forward and reverse data rate as needed during a TAP data connection, or change the application type between FETAP and RETAP as well as the associated forward and reverse transmission format (data rate) as needed during an ETAP data connection. If required, change other parameters (such as AT Directed Packets, etc.).

How Do I Change Call Parameters?

- "General Procedure"
- "To Configure the Test Set to FTAP/RTAP Protocols"
- "To Configure the Test Set to FETAP/RETAP Protocols"
- "To Configure the Test Set to Subtype 0 Physical Layer"
- "To Configure the Test Set to Subtype 2 Physical Layer"

General Procedure

- 1. Press the CALL SETUP key.
- 2. Select any Call Parms softkey (F7 to F12) to select a parameter.
- 3. Change the parameter as needed using the knob and/or keypad.
- 4. Select More (1 of 3) under Call Parms for additional call parameters.
- 5. Depending upon the current setting of the physical layer subtype, the Call Parms menus are different.
 - When the test set is configured to subtype 0 physical layer a typical display for Call Parms menu is shown as below.

Figure 4. Call Parms Menu (for Subtype 0 Physical Layer)

If you want to know more about the specific parameters, clock here.

l Setup Screen			
Cell Operating Mode	Call Parms		
	Cell Pouer	Call Parms	Call Parms
al Information (AT Reported)	-55.00	Rvs Pouer Ctrl	Session Close
	dBm/1.23 11Hz	Active bits	3
):	Cell Band		minutes
	US PCS	Pur Ctrl Step	Rcvr Pouer Ctrl
:	03 F03	1.0 dB	Auto
	0		
al Information (AN Assigned)	Channel	Call Drop Timer	
	525	On	
cation Configuration	Application Config	Call Limit Node	Neas Frequency
pe: Test Application		Off	Auto
col: FTAP	FTAP Rate		
Off	307.2 kbps	Protocol Rel	
50 Z	(2 Slot, QPSK)	0 (1xEV-D0)	
Attribute: On			
Node Attribute: On	RTAP Rate		
	9.6 kbps		
ell Sys Type: IS-856			
Logging: No Conn.			
ntRef Help PLSub0 FTAP	1 of 3		
		2 of 3	3 of 3

• When the test set is configured to subtype 2 physical layer (see "To Configure the Test Set to Subtype 2 Physical Layer" for detailed procedure), a typical display for Call Parms menu is shown as below.

Figure 5. Call Parms Menu (for Subtype 2 Physical Layer)

If you want to know more about the specific parameters, clock here.

jetup Screen				
l Operating Mode	Call P	arms	Call Parms	1
nformation (AT Reported)	Cell Poue	r	Rvs Pouer Ctrl	
	-55.	00	Active bits	Call Parms
	dBm/1	23 MHz		Session Close
	Cell Band		Pur Ctrl Step	3
	US P	CS	1.0 dB	minutes
nformation (AN Assigned)			110 00	Rcvr Pouer Ctrl
	Channel		Call Duca Timou	Auto
	52	5	Call Drop Timer On	
			UII	-
on Configuration				
	Applica	ation	Call Limit Node	_
Test Application Protocol: FETAP	Conf	'ig _⊽	Off	-Neas Frequency
50 Z		_		Auto
ibute: On	F-Traffic		Protocol Rel	
e Attribute: On	4 (1024,		A (1xEV-DO-A)	
jpe: Bi-Polar Keying	(307.2k	, QPSK)		
n Node: High Capacity	R-Data Pk	t Size		
s Rate: 9.6 kbps	128 t	oits	Protocol Subtype Config	
Cup Tuppe IC DEC]			
Sys Type: IS-856 Logging: No Conn.	l i			
eligging, No conn.	1 of	3		_
			2 of 3	-
Protocol Subtype Configura	ation	Va	alue	3 of 3
Release A Physical Layer Subtype		Subt	type 2	
PL Subtype 2 Access Channel NAC Sub	type	Enha	anced	

NOTE: The Protocol Subtype Configuration is shown only when Protocol Rel is set to A (1xEV-DO-A).

To Configure the Test Set to FTAP/RTAP Protocols

When the test set is configured to subtype 0 physical layer, the following parameters can be configured from the Application Configuration Window by selecting the Application Config (F10 on Call Parms 1 of 3).

		<u>т</u> ті	ne Session Application
Application Configuration	Value		ype is only shown in the
Session Application Type	Test Application		b application which
Test Application Protocol	FTAP		lows you to select Test oplication and Default
Limited TAP (AT Firmuare Rel 3.1)	Off		acket Application.
AT Directed Packets	50 %		
DRC Value Fixed flode Attribute	On		A 1:1:
ACK Channel Bit Fixed flode Attribute	On		Application
		FTAP	
		RTAP	

Figure 6. Application Configuration (for Subtype 0 Physical Layer)

- To establish an FTAP connection for AT's receiver test in subtype 0 physical layer, you should set Test Application Protocol to FTAP. Change other parameters as needed for your tests.
- To establish an RTAP connection for AT's transmitter test in subtype 0 physical layer, you should set Test Application Protocol to RTAP. Change other parameters as needed for your tests.
- (*Lap Application Only*) To establish a DPA connection for data application test, you should set Session Application Type to Default Packet Application.

Your settings are displayed in the Application Configuration window on the Call Setup screen. Also, the application (FTAP, RTAP or DPkt) and physical layer subtype (PLSub0) currently configured in the test set are displayed at the bottom of the screen.

Application Config	uration			
Session Application Type: Test Application				
Test Application Protocol:	FTAP			
Limited TAP:	Off			
AT Directed Packets: 50 %				
DRC Value Fixed Node Attribute:	On			
ACK Channel Bit Fixed flode Attribute: On				
Active Cell	Sys Type: IS-856			
Session Open	Logging: No Conn.			
IntRef	PLSub0 FTAP			

To Configure the Test Set to FETAP/RETAP Protocols

When the test set is configured to subtype 2 physical layer, the following parameters can be configured from the Application Configuration Window by selecting the Application Config (F10 on Call Parms 1 of 3).

Application Configuration	Value	
Session Application Type	Test Application	
Enhanced Test Application Protocol	FETAP	
AT Directed Packets	50 %	
DRC Value Fixed flode Attribute	On	Application
ACK Channel Bit Fixed Node Attribute	On	FETAP
ACK Channel Nodulation Type	Bi-Polar Keuino	RETAP
Reverse Data Transmission Node	High Capacity	
Enhanced Access Rate	9.6 kbps	

- To establish an FETAP connection for AT's receiver test in subtype 2 physical layer, you should set Enhanced Test Application Protocol to FETAP. Change other parameters as needed for your tests.
- To establish an RETAP connection for AT's transmitter test in subtype 2 physical layer, you should set Enhanced Test Application Protocol to RETAP. Change other parameters as needed for your tests.
- (Lap Application Only) The test set currently does not support DPA test in subtype 2 physical layer.

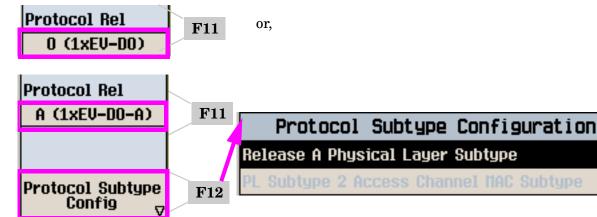
Your settings are displayed in the Application Configuration window on the Call Setup screen. Also, the application (FETAP or RETAP) and physical layer subtype (PLSub0 or PLSub2) being configured in the test set are displayed at the bottom of the screen.

Application Configur	ation		
Session Application Type: Enhanced Test Application Protocol: AT Directed Packets: DRC Value Fixed Node Attribute: ACK Channel Bit Fixed Node Attribute: ACK Channel Nodulation Type: Reverse Data Transmission Node:	FETA 50 3 On On Bi-P High	z Z olar Keying Capacity	
Expected Enhanced Access Rate:	Unkr	юцп	
Active Cell		Sys Type: IS-856	
Session Open		Logging: No Conn.	
IntRef Offset		PLSub2 FET	AP

To Configure the Test Set to Subtype 0 Physical Layer

To configure the test set to subtype 0 physical layer,

- set the Protocol Rel (F11 on Call Parms 2 of 3) to 0 (1 xEV-DO), or
- set the Protocol Rel (F11 on Call Parms 2 of 3) to A (1xEV-DO-A) and set the Release A Physical Layer Subtype to Subtype 0 from the Protocol Subtype Configuration menu by pressing the F12 (Protocol Subtype Config).



To Configure the Test Set to Subtype 2 Physical Layer

To configure the test set to subtype 2 physical layer, set the Protocol Rel (F11 on Call Parms 2 of 3) to A (1xEV-DO-A) and set the Release A Physical Layer Subtype (F12 on Call Parms 2 of 3) to Subtype 2 from the Protocol Subtype Configuration menu by pressing the F12 (Protocol Subtype Config).

Value

Subtype 0

Protocol Rel		
A (1xEV-DO-A)	F11	
	Protocol Subtype Configuration	Value
	Release A Physical Layer Subtype	Subtype 2
Protocol Subtype Config ₇₇	F12 PL Subtype 2 Access Channel NAC Subtype	Enhanced

How Do I Change Cell Parameters?

A. Select the Cell Parameters Menu.

- 1. Press the CALL SETUP key.
- 2. Press the left More key, go to Call Control 2 of 2 (in the Test Application) or Call Control 2 of 3 (in the Lab Application).
- 3. Select Access Network Info (F2), go to AN Info menu.
- 4. Select Cell Parameters (F2).

AN Info	Access Network Information			
Configurable Attribute Ctrl _⊽	Physical Layer Subtype In Use: PLSub0			
Cell Parameters _⊽	Rate 1118 Supported In Use: No Cell Parameters			
Channel Gain / Traffic Info Access Parameters _V	Sector ID (Hex): FEA0:0000:0000:0000:0000:0000:0000Country Code:310Color Code:64Subnet Mask:104Control Channel Data Rate:76.8 dBPreferred Control Channel Cycle:0ffPilot Drop:18 (-9.0 dB)			
CDIIA System Time / Sync Info Return	Access Parameters Open Loop Adjust: 81 dB Probe Sequence flax: Probe Initial Adjust: 0 dB Preamble Length (Frames): Probe Pouer Step: 1.0 dB Preamble Length Slots: 1 Probe Num Step: 5			

B. Set a Cell Parameter.

1. Turn the knob to highlight a parameter and then press the knob.

Cell Parameters	Value	
Sector ID, Louer Hiddle (Hex)	0000000	ŧ
Sector ID, Louer (Hex)	0000001	
Country Code	310	
Color Code	64	
Subnet flask	104	
Control Channel Data Rate	76.8 kbps	
Preferred Control Channel Cycle	Off	
Pilot Drop	18	

- 2. Enter a value or selection and press the knob.
- 3. Select Close Menu (F6).

How Do I Change Access Parameters?

- "General Procedure"
- "To Configure the Test Set to Default Access Channel MAC Subtype"
- "To Configure the Test Set to Enhanced Access Channel MAC Subtype"

General Procedure

A. Select the Access Parameters Menu.

- 1. Press the CALL SETUP key.
- 2. Press the left More key, go to Call Control 2 of 2 (in the Test Application) or Call Control 2 of 3 (in the Lab Application).
- 3. Select Access Network Info (F2), go to AN Info menu.
- 4. All access parameters are available by pressing the F4 on AN Info menu. Depending upon the current setting of the Access Channel MAC Subtype, the F4 is labeled as either Access Parameters or Enhanced Access Parameters .
 - When the test set is configured to Default Access Channel MAC Subtype the **F4** is labeled as Access Parameters.
 - When the test set is configured to Enhanced Access Channel MAC Subtype for detailed procedure), the F4 is labeled as Enhanced Access Parameters.

How Do I Change Access Parameters?

5. Select **F4**. A typical display for the Access Parameters menu or the Enhanced Access Parameters menu is shown as below.

Access Parameters	Value
Open Loop Adjust	81 dB
Probe Initial Adjust	0 dB
Probe Pouer Step	1.0 dB
Probe Num Step	5
Probe Sequence Nax	1
Preamble Length (Frames)	2
Enhanced Access Parameters	Value
Enhanced Access Parameters Open Loop Adjust	Value 81 dB
Open Loop Adjust	81 dB
Open Loop Adjust Probe Initial Adjust	81 dB O dB
Open Loop Adjust Probe Initial Adjust Probe Pouer Step	81 dB 0 dB 1.0 dB
Open Loop Adjust Probe Initial Adjust Probe Pouer Step Probe Num Step	81 dB 0 dB 1.0 dB 5

B. Set an Access Parameter.

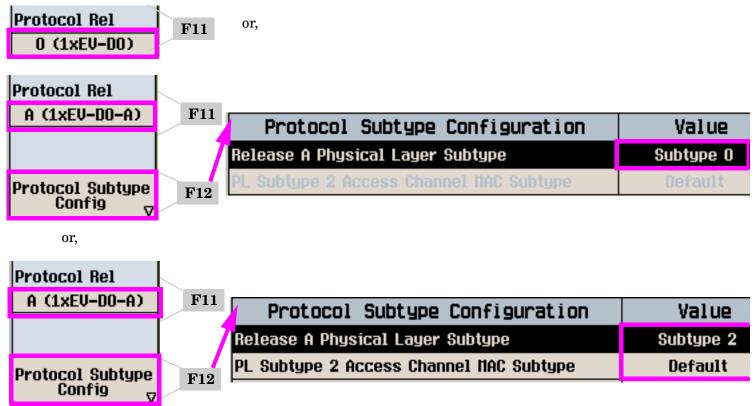
- 1. Turn the knob to highlight a parameter and then press the knob.
- 2. Enter a value or selection and press the knob.
- 3. Select Close Menu (F6).

To Configure the Test Set to Default Access Channel MAC Subtype

To configure the test set to Default Access Channel MAC Subtype,

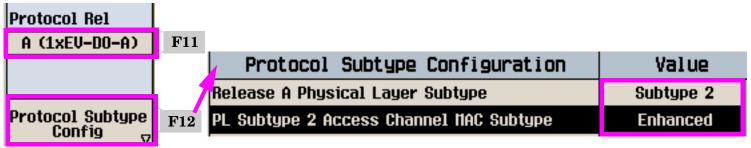
- set the Protocol Rel (F11 on Call Parms 2 of 3) to 0 (1xEV-DO), or
- set the Protocol Rel (F11 on Call Parms 2 of 3) to A (1xEV-DO-A) and set the Release A Physical Layer Subtype to Subtype 0 from the Protocol Subtype Configuration menu by pressing the F12 (Protocol Subtype Config).

• set the Protocol Rel(F11) to A (1xEV-DO-A), set the Release A Physical Layer Subtype to Subtype 2 and PL Subtype 2 Access Channel MAC Subtype to Default from the Protocol Subtype Configuration menu by pressing the F12 (Protocol Subtype Config).



To Configure the Test Set to Enhanced Access Channel MAC Subtype

To configure the test set to Enhanced Access Channel MAC Subtype, set the Protocol Rel(F11) to A (1xEV-DO-A), set the Release A Physical Layer Subtype to Subtype 2 and PL Subtype 2 Access Channel MAC Subtype to Enhanced from the Protocol Subtype Configuration menu by pressing the F12 (Protocol Subtype Config).



How Do I Change Channel Gain/Traffic Info Parameters?

A. Select the Channel Gain Info or Channel Gain/Traffic Info menu

- 1. Press the CALL SETUP key.
- 2. Press the left More key, go to Call Control 2 of 2 (in the Test Application) or Call Control 2 of 3 (in the Lab Application).
- 3. Select Access Network Info (F2), go to AN Info menu.
- 4. Depending upon the current setting of the physical layer subtype, the **F3** on AN Info menu is labeled as either Channel Gain Info (for subtype 0 physical layer) or Channel Gain / Traffic Info (for subtype 2 physical layer) which allows you to access different parameters. For detailed procedure on how to configure the physical layer subtype, see "To Configure the Test Set to Subtype 0 Physical Layer" and "To Configure the Test Set to Subtype 0 Physical Layer" respectively.
 - Press the F3 (Channel Gain Info), set the parameters as demonstrated at "B1. Set parameters accessed from F3 (Channel Gain Info)"
 - Press the F3 (Channel Gain / Traffic Info), set the parameters as demonstrated at "B2. Set parameters accessed from F3 (Channel Gain/Traffic Info)"

B1. Set parameters accessed from F3 (Channel Gain Info)

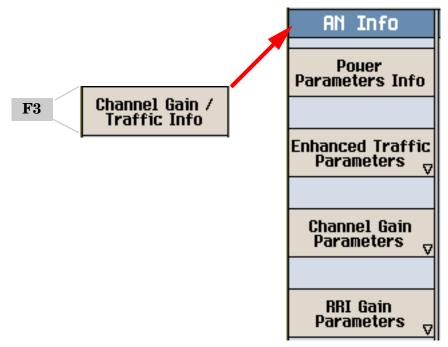
- 1. When the F3 (Channel Gain Info) is pressed, the channel gain parameters can be accessed.
- 2. Select Channel Gain Parameters (F3).

Channel Gain Parameters	Value
Data Offset Nom	0.0 dB
Data Offset 9k6	0.00 dB
Data Offset 19k2	0.00 dB
Data Offset 38k4	0.00 dB
Data Offset 76k8	0.00 dB
Data Offset 153k6	0.00 dB
ACK Channel Gain	3.0 dB
DRC Channel Gain	3.0 dB

- 3. Turn the knob to highlight a parameter and then press the knob.
- 4. Enter a value or selection and press the knob.
- 5. Select Close Menu (F6).

B2. Set parameters accessed from F3 (Channel Gain/Traffic Info)

1. When the F3 (Channel Gain / Traffic Info) is pressed, more parameters relating to subtype 2 physical layer can be accessed.



• To set subtype 2 physical layer T2P related parameters, select Power Parameters Info (F1). A typical display is shown as below. Note that all of the T2P parameters for each data packet size and transmission mode are displayed on the Power Parameters screen. Which set of T2P parameters being applied in the test set (current values) is identified by a '>' indicator.

AN Info	Access Network Information								
T2P Setup Ctr1									
512				Douer	Daramo	tore			
bits	R-Packet	Power Parameters R-Packet Low Latency High Capacity							
	Size	T2P		Pre-	Post-	T2P	Term	Pre-	Post-
512-bit Pouer	(bits)	Trans			Trans			Trans	
Parameters _V		(subpa	acket)	(di	30	(subpa	icket)	(d	B)
	128	1	1	7.00	0.75	3	3	0.75	0.75
	256	1	1	10.00	3.75	3	3	3.75	3.75
	512	1	1	13.00	7.00	> 3	3	7.00	7.00
	768	1	1	14.75	8.75	3	3	8.75	8.75
	1024	1	1	16.25	10.00	3	3	10.00	10.00
	1536	1	1	18.25	11.50	3	3	11.50	11.50
	2048	1	1	19.25	13.00	3	3	13.00	13.00
	3072	1	1	19.25	14.25	3	3	14.25	14.25
	4096	1	1	20.50	15.50	3	3	15.50	15.50
	6144	1	1	21.75	17.00	3	3	17.00	17.00
	8192	1	1	23.25	18.50	3	3	18.50	18.50
	12288	1	1	26.25	21.25	3	3	21.25	21.25
Return									

- Press F1 (T2P Setup Ctrl), select a R-Data packet size (for example, 512 bits). F2 is labeled according to the F1 setting (in this example, 512-bit Power Parameters is labeled for F2).

 Press F2, set the T2P parameters (such as T2P Transition value, Termination Target value, TxT2P Pre-Transition and Post-Transition gain values) for the specified packet size.

512-bit Power Parameters	Value
512-bit Lou Latency T2P Transition	1
512–bit Lou Latency Termination Target	1
512-bit Lou Latency TxT2P Pre-Transition	13.00 dB
512-bit Lou Latency TxT2P Post-Transition	7.00 dB
512–bit High Capacity T2P Transition	3
512–bit High Capacity Termination Target	3
512-bit High Capacity TxT2P Pre-Transition	7.00 dB
512–bit High Capacity TxT2P Post–Transition	7.00 dB

• To set the following enhanced parameters for subtype 2 physical layer, select Enhanced Traffic Parameters (F2).

Enhanced Traffic Parameters	Value
Auxiliary Pilot Channel Hin Payload	3072 bits
DSC Length	64 slots
Short Packets Enabled Threshold	2048 bits

• To set the subtype 2 reverse channel gain, select Channel Gain Parameters (F3). Note that the R-Data channel gains are set from the Power Parameters Info menu and the RRI channel gains are set from the RRI Gain Parameters menu.

Channel Gain Parameters	Value
Data Offset Nom	0.0 dB
Data Offset 9k6	0.00 dB
Data Offset 19k2	0.00 dB
Data Offset 38k4	0.00 dB
ACK Channel Gain	3.0 dB
DRC Channel Gain	3.0 dB
DSC Channel Gain	-9.0 dB
Auxiliary Pilot Channel Gain	-12 dB

• To set the subtype 2 R-RRI channel gain, select RRI Gain Parameters (F4).

RRI Channel Gain Parameters	Value
RRI Channel Gain Pre-Transition O	0 dB
RRI Channel Gain Post-Transition O	-6 dB
RRI Channel Gain Pre-Transition 1	0 dB
RRI Channel Gain Post-Transition 1	-6 dB
RRI Channel Gain Pre-Transition 2	-6 dB
RRI Channel Gain Post-Transition 2	-6 dB
RRI Channel Gain Pre-Transition 3	-6 dB

2. Turn the knob to highlight a parameter and then press the knob.

3. Enter a value or selection and press the knob.

4. Select Close Menu (F6).

How Do I Change Generator Information?

A. Select the Generator Info Menu.

- 1. Press the CALL SETUP key.
- Press the left More key, go to Call Control 2 of 2 (in the Test Application) or Call Control 2 of 3 (in the Lab Application).
- 3. Select Generator Info $(\mathbf{F3})$ go to Gen Info menu.
- 4. Depending upon the current physical layer subtype, the Generator Info menu provides different parameters for your access.
 - When the test set is configured to subtype 0 physical layer (see "To Configure the Test Set to Subtype 0 Physical Layer" for detailed procedure), a typical display for Gen Info menu is shown as below.

Gen Info		
AUGN Pouer		
Off		
PN Offset		
12		
	Termination Parameters	Values
External Trigger	🔁 Nax Foruard Packet Duration	16 slots
2.00 s		
Termination Parameters _V		
Y Y		

How Do I Change Generator Information?

• When the test set is configured to subtype 2 physical layer (see "To Configure the Test Set to Subtype 2 Physical Layer" for detailed procedure), a typical display for Gen Info menu is shown as below.

Gen Info	Code Channel Parameters	Values
Code Channel	H-ARQ Modulation	Bi–Polar Keying
Parameters 🕁	H-ARQ/L-ARQ Channel Level	-9.00 dB
AUGN Pouer	P-ARQ Channel Level	-9.00 dB
Off	RPC Channel Level	-9.00 dB
PN Offset		
12		
External Trigger		
2.00 s	Termination Parameters	Values
	Nax Foruard Packet Duration	16 slots
Termination Parameters 🚽	ACK R-Data After	Never (All NAK)
Parameters _▽		

B. Set parameters on Gen Info menu.

- 1. Select any Gen Info softkey $(F1 \ to \ F5)$ to select a parameter.
- 2. Change the parameter as needed using the knob and/or keypad.

How Do I Change Configurable Attribute Control Mode?

A. Select the Configurable Attribute Control Menu.

- 1. Press the CALL SETUP key.
- Press the left More key, go to Call Control 2 of 2 (in the Test Application) or Call Control 2 of 3 (in the Lab Application).
- 3. Select Access Network Info $({\bf F2}).$
- 4. Select Configurable Attribute Parms $({\bf F1}).$

Call Control	AN Info	Access Network Information
Access Network Info	Configurable Attribute Parms _v Cell Parameters _v	Physical Layer Subtype In Use: PLSub0 Access Channel MAC Subtype In Use: Default
Generator Info	Channel Gain Info Access Parameters _V	Cell ParametersSector ID (Hex): FEA0:0000:0000:0000:0000:000Country Code:310Color Code:64Subnet flask:104Control Channel Data Rate:76.8 kbpsPreferred Control Channel Cucle:0ff
	CDNA System Time / Sync Info Return	Access ParametersOpen Loop Adjust:81 dBProbe Sequence flax:Probe Initial Adjust:0 dBPreamble Length (FraProbe Pouer Step:1.0 dBProbe Num Step:5
2 of 3		Active Cell Sys Type Idle Logging: DBUS-INT IntRef Help PL

5. The parameters under Configurable Attribute Control menu are different depending upon the current physical layer subtype.

How Do I Change Configurable Attribute Control Mode?

• When the test set is configured to subtype 0 physical layer (see "To Configure the Test Set to Subtype 0 Physical Layer" for detailed procedure), a typical display for Configurable Attribute Control menu is shown as below.

Configurable Attribute Control	Value
Preferred Control Channel Cycle Control	AN Specified

• When the test set is configured to subtype 2 physical layer (see "To Configure the Test Set to Subtype 0 Physical Layer" for detailed procedure), a typical display for Configurable Attribute Control menu is shown as below.

Configurable Attribute Control	Value
Preferred Control Channel Cycle Control	AN Specified
Rate 1118 Supported Control	AN Specified

B. Set the Control Mode for a Configurable Attribute.

IMPORTANT You can not change the session negotiation control mode for a configurable attribute when a session is open and Call Limit Mode is on (because the test set would not be able to establish a traffic connection to re-negotiate the value when call limit mode is on).

- 1. Turn the knob to highlight a parameter and then press the knob.
- 2. Enter a value or selection and press the knob.
- 3. Select Close Menu (F6).

Calibrating the Test Set

Description

- "Calibration Process Requirements"
- "Recommended Calibration Intervals"
- "Calibration Descriptions"
 - "IQ Calibrations"
 - "Burst Mod Offset 1 Calibration"
 - "Digital Average Power Calibration"
 - "Spectrum Monitor Calibration"
 - "Calibrate Measurements"
 - "Channel Power Calibration"

Various calibration routines must be run periodically to ensure measurement accuracy, source accuracy and allow the most robust demodulation of the device-under-test's signal. This document describes the various calibrations available in the test set and when they should be performed.

Calibration Process Requirements

IMPORTANT Before performing any calibrations on your test set:

- *Ensure that the calibration is necessary* running calibrations more often than necessary wastes your time and effort, and if the calibration is performed incorrectly, could actually result in degraded test set performance.
- *Ensure that the test set is in its ambient operating environment* in other words, ensure that the test set has warmed up (at least 30 minutes) and is in a location similar to the one it will be used in. For example, if you are going to be using the test set in a racked test system, then you must calibrate the test set while it is in that test system, and all of the equipment has reached a stable operating temperature.
- *Ensure that no power is present at the front panel RF connectors* remove any cables or connectors from the RF IN/OUT and RF OUT ONLY connectors. If you are operating in a high RF environment, it is recommended that you also terminate the RF connectors with a 50 Ohm load.

Recommended Calibration Intervals

This section indicates when the test set calibrations should be performed. Procedures are given for test sets that include *Option 003: Flexible Radio Link* and test sets that do not. Refer to "Calibration Descriptions" on page 100 for details about the calibrations and how to perform them.

Calibrating the Test Set

- Once every year you must perform a full calibration by following steps 1-6 of the "Calibration Procedure for Test Sets with Option 003" (or steps 1-2 of the "Calibration Procedure for Test Sets without Option 003" if your test set does not include option 003).
- You must also perform steps 1-6 of the "Calibration Procedure for Test Sets with Option 003" (or steps 1-2 of the "Calibration Procedure for Test Sets without Option 003" if your test set does not include option 003) if any of the following events occur:
 - When you receive the test set, before using it for the first time (regardless of whether the test set is new, being returned from service, or on loan from a colleague).
 - After adding a NEW application or format to the test set.
 Note: *upgrading firmware* in the test set does not typically require running the calibration procedures.
 However, when upgrading firmware, it is advisable to check the release notes for any major feature changes that require re-calibration of the test set.
 - After you perform any kind of repair or service on your test set.
- It is recommended that once every month you perform steps 4-6 of the "Calibration Procedure for Test Sets with Option 003" (or step 2 of the "Calibration Procedure for Test Sets without Option 003" if your test set does not include option 003).
- You must also perform steps 4-6 of the "Calibration Procedure for Test Sets with Option 003" (or step 2 of the "Calibration Procedure for Test Sets without Option 003" if your test set does not include option 003) if any of the following events occur:
 - The operating environment for your test set changes significantly (for example, the temperature changes by more than 10 degrees C or the test set is moved from a racked test system to a bench top).
 - A measurement returns integrity indicator 19 (Uncalibrated Due to Temperature).

IMPORTANT Ensure that your test set has warmed up at least 30 minutes and that no power is present at the front panel RF connectors before performing any calibrations.

Calibration Procedure for Test Sets with Option 003

	Calibration Interval = 1 year			Calibration Interval = 1 month		
Application or Format	IQ Calibrations (See Note 1)	Burst Mod Offset 1 Calibration	Digital Average Power Calibration	Spectrum Monitor Calibration	Channel Power Calibration	Calibrate Measurements
cdma2000/ IS-95/AMPS	Step 1	Step 2	Step 3A Perform once from one of these applications or	Step 4	Covered by	
1xEV-DO	Perform IQ1and IQ2 once from one of these	Perform once from one of these applications	formats Step 3B Cycle Power	from one of these applications or formats	Step 4 (See Note 2)	
W-CDMA	applications or formats	or formats		Step 5 Perform once from this application		Covered by Step 5 (See Note 2)
GSM/GPRS/ EGPRS AMPS/136				Step 6 Perform once from one of these applications or formate		
Note 1 – Calibrate Second IQ Modulator only applies to instruments with Option 002: RF Source 2. Note 2 – You do not need to run this calibration if Spectrum Monitor calibration is run first.						

Calibrating the Test Set

	Calibration Interval = 1 year Calibration Interval = 1 month				
Application or Format	or Format IQ Calibrations (See Note 1) Spectrum Monitor C				
GSM/GPRS/EGPRS	Step 1	Step 2			
AMPS/136	Perform IQ1and IQ2 once from one of these applications or formats	Perform once from one of these applications or formats			
Note 1 – Calibrate Second IQ Modulator only applies to instruments with Option 002: RF Source 2.					

Calibration Descriptions

IQ Calibrations When performed from a GSM/GPRS/EGPRS or AMPS/136 application or format, the First IQ Modulator calibration sends a signal from the Baseband Generator 1 module to the RF Source 1 module to optimize the phase accuracy of RF Source 1 as a function of frequency. The optimization data is then stored in the test set and accessed whenever the RF Source frequency is set. The Second IQ Modulator calibration performs a similar procedure for RF Source 2 (RF Source 2 is only present if the test set includes option 002: RF Source 2).

When performed from a W-CDMA, cdma2000/IS-95/AMPS or 1xEV-DO application or format (which require option 003: Flexible Radio Link), the IQ calibrations perform the same phase optimizations explained above. Additionally, a signal is sent from the Flexible Radio Link Subsystem to the RF sources to calibrate phase accuracy for those alternative paths as well. This additional calibration data is written to the same calibration data file as above, but in a different area of the calibration table.

The IQ calibrations ensure that the test set accurately generates IQ-modulated signals. If the test set's IQ modulators have not been properly calibrated, the test set's output power (when producing an IQ-modulated signal) will be inaccurate, which may result in degraded receiver test results.

If you perform the IQ calibrations from a W-CDMA, cdma2000/IS-95/AMPS or 1xEV-DO application or format, you do not need to perform them from any other application or format. However, note that if you perform the IQ calibrations from a GSM/GPRS/EGPRS or AMPS/136 application/format, you must still perform them once from a W-CDMA, cdma2000/IS-95/AMPS or 1xEV-DO application or format.

The IQ calibrations do not need to be run frequently. See "Recommended Calibration Intervals" on page 97.

To initiate the IQ calibrations from the front panel, press **SYSTEM CONFIG**, press the right **More** (1 of 2) key, select Service (**F7**), then select Cal. first IQ Modulator or Cal. second IQ Modulator. To initiate the IQ calibrations from a remote program, use the CALibration:IQ[1]|2? queries.

Each IQ calibration takes 5-6 minutes to execute.

Burst Mod Offset 1 Calibration This calibration is only applicable to W-CDMA, cdma2000/IS-95/AMPS, and 1xEV-DO applications and formats. This calibration is only required when using the test set to generate an AM or DSB-SC test signal (select (**F9**) Test Signal when in CW Operating Mode). These test signals are used for calibrating Zero Intermediate Frequency (Zero IF) devices which utilize Qualcomm's radioOneTM

architecture.

You do not have to perform the Burst Mod Offset 1 calibration for each application/format in your test set; performing it from one application/format provides calibration data to all relevant applications and formats.

The Burst Mod Offset 1 calibration does not need to be run frequently. See "Recommended Calibration Intervals" on page 97.

The Burst Mod Offset 1 calibration calibrates the noise and signal level of RF Source 1 (as a function of frequency) to most accurately produce the AM and DSB-SC test signals required for Zero IF device calibration. The calibration is performed by generating the modulated test signals and adjusting RF Source 1 to optimize gain and minimize the noise floor. The optimization data is then stored in the test set and accessed whenever the RF Source frequency is set.

To initiate the Burst Mod Offset 1 calibration from the front panel, press SYSTEM CONFIG, press the right More (1 of 2) key, select Service (F7), then select Cal. Burst Mod Offset 1. To initiate the Burst Mod Offset 1 calibration from a remote program, use the CALibration: BMOFfset? query.

The Burst Mod Offset 1 calibration takes less than 1 minute to execute.

Digital Average Power Calibration The Digital Average Power calibration is only applicable to the cdma2000/IS-95/AMPS and 1xEV-DO applications/formats.

You do not have to perform the Digital Average Power calibration for each application/format in your test set; performing it from one application/format provides calibration data to all relevant applications and formats.

The Digital Average Power calibration does not need to be run frequently. See "Recommended Calibration Intervals" on page 97.

IMPORTANT You *must* cycle the test set's power after the Digital Average Power calibration is complete in order to complete the calibration (the calibration data is not available to the test set until it has been restarted).

The Digital Average Power calibration generates calibration data for the Fast Power Detector for use by cdma2000/IS-95/AMPS and 1xEV-DO applications and formats. The calibration is performed by generating a CW signal at a given power level, measuring it using the Fast Power Detector, then generating and measuring a CDMA-modulated signal at the same power level and noting the difference. This is repeated for several power levels.

The Digital Average Power calibration provides calibration data for the following measurements:

- Digital Average Power
- Maximum/Minimum Power

To initiate the Digital Average Power calibration from the front panel, press Measurement selection, select Digital Average Power, then select Calibrate Digital Avg Pwr (F4). To initiate the Digital Average Power calibration from a remote program, use the CALibration:DAPower? query.

The Digital Average Power calibration takes approximately 9 minutes to execute.

Spectrum Monitor Calibration Performing the Spectrum Monitor calibration from one application/format does not provide calibration data to all relevant applications and formats. The calibration data files are shared as follows:

Calibrating the Test Set

- cdma2000/IS-95/AMPS and 1xEV-DO share the same Spectrum Monitor calibration data file.
- W-CDMA has its own Spectrum Monitor calibration data file.
- GSM/GPRS/EGPRS and AMPS/136 share the same Spectrum Monitor calibration data file.

Thus, if you perform the Spectrum Monitor calibration from a 1xEV-DO application/format, you do not need to perform it from a cdma2000/IS-95/AMPS application/format. However you do still need to perform it from a W-CDMA application/format and then again from either a GSM/GPRS/EGPRS or AMPS/136 application/format.

The Spectrum Monitor calibration should be run monthly, or whenever the test set's operating environment changes. See "Recommended Calibration Intervals" on page 97.

Performing the Spectrum Monitor calibration from a cdma2000/IS-95/AMPS or 1xEV-DO application/format executes the same routine as performing the "Channel Power Calibration" on page 103.

Performing the Spectrum Monitor calibration from a W-CDMA application/format executes the same routine as performing the "Calibrate Measurements" on page 102 routine.

Performing the Spectrum Monitor calibration from a GSM/GPRS/EGPRS or AMPS/136 application/format calibrates the IF signal path in the Measurement Downconverter, using a CW signal.

To initiate the Spectrum Monitor calibration from the front panel, press Instrument selection, select Spectrum Monitor, select Trigger Setup (F4), then select Calibrate Measurement (F11). To initiate the Spectrum Monitor calibration from a remote program, use the CALibration: SMONitor? query.

The Spectrum Monitor calibration takes between 45 seconds and 3 minutes to execute, depending upon which application/format it is executed from.

Calibrate Measurements The Calibrate Measurements routine is only applicable to W-CDMA applications/formats.

The Calibrate Measurements routine should be run monthly, or whenever the test set's operating environment changes. See "Recommended Calibration Intervals" on page 97.

The Calibrate Measurements routine calibrates the signal paths through the Measurement Downconverter and Demod Downconverter using both a CW signal and a modulated signal. The calibration is performed by comparing measured signals through the MDC and DDC to measurements made using the Fast Power Detector (which is calibrated at the factory and temperature controlled for stability). During the Calibrate Measurements calibration, the internal temperature of the test set is measured and stored with the calibration data. If the internal temperature of the test set drifts by more than +/- 10 C since the last calibration, measurements utilizing this calibration will return integrity indicator 19 (Uncalibrated Due to Temperature).

The Calibrate Measurements routine provides calibration data for the following measurements:

- Adjacent Channel Leakage Ratio
- Channel Power
- Change of TFC (lab application only)
- Code Domain
- Dynamic Power Analysis
- Fast Device Tune (*lab application or feature-licensed test application only*)

- Inner Loop Power
- IQ Tuning
- Occupied Bandwidth
- Phase Discontinuity
- PRACH Preamble Analysis (lab application only)
- PRACH Transmit On/Off Power
- Spectrum Emission Mask
- Spectrum Monitor
- TX Dynamic Power
- Waveform Quality

Performing the Calibrate Measurements routine executes the same routine as performing the "Spectrum Monitor Calibration" on page 101 from a W-CDMA application/format.

To initiate the Calibrate Measurements routine from the front panel, initiate any of the measurements listed above and select Calibrate Measurements (F4). To initiate the Calibrate Measurements routine from a remote program, use the CALibration:MEASurements? query.

The Calibrate Measurements routine takes approximately 3 minutes to execute.

Channel Power Calibration The Channel Power calibration is applicable to the cdma2000/IS-95/AMPS and 1xEV-DO applications/formats.

You do not have to perform the Channel Power calibration for each application/format in your test set; performing it from one application/format provides calibration data to all relevant applications and formats.

The Channel Power calibration should be run monthly, or whenever the test set's operating environment changes. See "Recommended Calibration Intervals" on page 97.

The Channel Power calibration calibrates the signal paths through the Measurement Downconverter and Demod Downconverter using both a CW signal and a modulated signal. The calibration is performed by comparing measured signals through the MDC and DDC to measurements made using the Fast Power Detector (which is calibrated at the factory and temperature controlled for stability). During the Calibrate Measurements calibration, the internal temperature of the test set is measured and stored with the calibration data. If the internal temperature of the test set drifts by more than +/- 10 C since the last calibration, measurements utilizing this calibration will return integrity indicator 19 (Uncalibrated Due to Temperature).

The Channel Power calibration provides calibration data for the following measurements:

- Access Probe Power
- Channel Power
- Code Channel Time/Phase Error
- Fast Device Tune (*lab application or feature-licensed test application only*)
- Gated Power
- Graphical Access Probe Power (*lab application only*)

Calibrating the Test Set

- Handoff Waveform Quality
- Maximum/Minimum Power
- Time Response of Open Loop Power Control
- TX Dynamic Power
- TX Spurious Emissions
- Waveform Quality + Code Domain
- Spectrum Monitor

Performing the Channel Power calibration executes the same routine as performing the "Spectrum Monitor Calibration" on page 101 from a cdma2000/IS-95/AMPS or 1xEV-DO application/format.

To initiate the Channel Power calibration from the front panel, initiate any of the measurements listed above and select Calibrate Channel Power (F4). To initiate the Channel Power calibration from a remote program, use the CALibration:CPOWer? query.

The Channel Power calibration takes approximately 2 minutes to execute.

Amplitude Offset

Description

Amplitude offsets compensate for loss or gain between the test set's RF IN/OUT front panel connector and the mobile station's RF connector.

To access the amplitude offset feature, press the SYSTEM CONFIG key, followed by the RF IN/OUT Amptd offset (F5) key.

Amplitude offset settings are preserved during power cycles or instrument preset.

Setting Up Amplitude Offsets and Frequency Points

Up to 20 frequency points can be assigned an amplitude offset. Negative amplitude offset values should be entered when there is a loss through the RF cabling and test fixtures and positive values should be entered when there is a gain.

The RF IN/OUT Amplitude Offset table displays the current (on/off) state of the amplitude offset feature. There are also 20 rows for entering frequencies and 20 rows for entering corresponding offset values. To enter values in the table use the RF IN/OUT Amplitude Offset Setup menu.

To set up amplitude offsets remotely, one comma-separated string is sent to set up frequency points and another comma-separated string assigns the corresponding amplitudes.

GPIB Commands

OUTPUT 714; "SYSTEM: CORRECTION: SFREQUENCY 1710.2 MHZ, 1805.2 MHZ, 1784.8 MHZ, 1879.8 MHZ" !sets the first 4 frequencies in the amplitude offset table.

OUTPUT 714; "SYSTEM: CORRECTION: SGAIN -2.55, -3.12, -3.68, -4.23" !sets the first 4 amplitude offsets in the amplitude offset table.

Turning amplitude offsets on/off

When the RF IN/OUT Amplitude Offset State is on, all offsets that are not individually turned off are applied and the word "Offset" appears in the Instrument Status Area of the test set's display.

If the RF IN/OUT Amplitude Offset State is off, none of the amplitude offsets are applied.

GPIB Command

OUTPUT 714; "SYSTEM:CORRECTION:STATE ON" !Sets the RF IN/OUT Amplitude Offset State to On

NOTE If the RF IN/OUT Amplitude Offset State is turned off, none of the amplitude offsets are on, even if values are entered for the individual offsets.

Examples of Amplitude Offset Behavior

When the amplitude offset table entries accurately represent the loss in all components (cabling, connectors, and test fixturing) in the signal path between the test set and the mobile station, the test set will make the necessary adjustments in both receiver and transmitter measurements.

Amplitude Offset

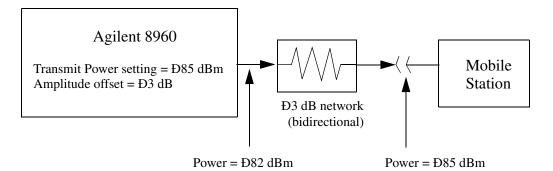
Mobile Station Receiver Example

When you set a transmit power level, the test set uses the amplitude offset value to adjust the power so that the test set's transmit power level refers to the power level received at the mobile station.

As shown in Figure 8. "Amplitude Offset Mobile Station Receiver Example", with the test set's transmit power set to -85 dBm and a -3 dB amplitude offset the actual power level transmitted from the test set will be automatically offset to -82 dBm. With a 3 dB loss in the signal path the mobile station will receive -85 dBm, the actual setting.

Figure 8.

Amplitude Offset Mobile Station Receiver Example



Mobile Station Transmitter Example

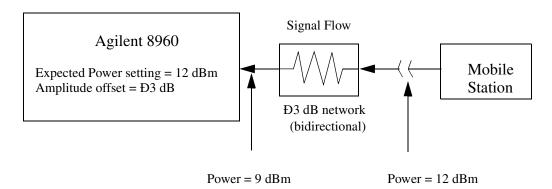
When you measure power from the mobile station, the displayed and queried values are offset to show the level at the mobile station.

As shown in Figure 9. "Amplitude Offset Mobile Station Transmitter Example", with the mobile station transmitting 12 dBm and a -3 dB amplitude offset is entered, the measured power at the test set would be 9 dBm. The displayed power level is automatically adjusted to 12 dBm to show the level at the mobile station.

If the expected power, which can be set manually or automatically is 12 dBm, the test set's internal hardware adjusts itself to receive 9 dBm which is the actual power from the mobile station after 3 dB loss in the network.

Figure 9.

Amplitude Offset Mobile Station Transmitter Example



Amplitude Offsets Between Frequency Settings

If mobile station testing is performed at frequencies that do not have amplitude offsets assigned to them, the test set will estimate an amplitude offset based on the nearest settings. For example, the following screen shows five amplitude offsets for frequencies ranging from 890.2 MHz to 1710.2 MHz.

System Config Screen					
RF IN/OUT	RF IN/OUT Amplitude Offset	Utilities			
	RF IN/OUT Amplitude Offset State: On <u>Number</u> <u>Frequency (11Hz)</u> <u>Offset (dB)</u>	llessage Log			
BF IN/OUT Amptd	1 890.20 -1.00 2 890.60 -2.00 3 891.00 -3.00				
Offset Setup _V	4 914.00 -4.00 5 1710.20 -4.50 6 Off Off				
	7 Off Off 8 Off Off				
	RF IN/OUT Amplitude Offset Setup Value				
	RF In/Out Amplitude Offset State On				
	Frequency 1 890.200 MHz				
	Offset 1 -1.00 dB				
	Frequency 2 890.600 MHz				
	Offset 2 -2.00 dB				
	Frequency 3 891.000 MHz				
Close	Offset 3 -3.00 dB				
Henu	Frequency 4 914.000 MHz 🚽				
	Active Cell Sys Type: IS-2000				
	IntRef Offset	1 of 2			

Figure 10. RF IN/OUT Amplitude Offset Setup

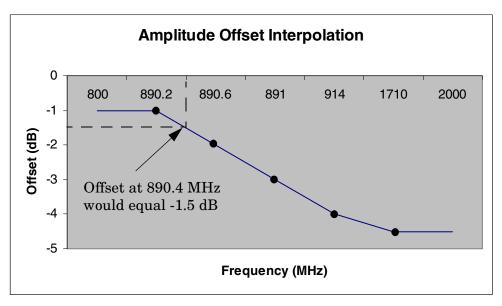
For test frequencies between the lowest (890.2 MHz) and highest (1710.2 MHz) frequency points that are not entered in the table, the test set will calculate offsets using piece-wise linear interpolation.

The graph shown in Figure 11. "Amplitude Offset Interpolation" is a conceptual representation of the test set's amplitude offset configuration using the settings from the RF IN/OUT Amplitude Offset table in Figure 10. "RF IN/OUT Amplitude Offset Setup". Each of the five points are shown on a non-scaled frequency versus amplitude offset graph. At a test frequency of 890.4 MHz, which is midway between point number one (-1 dB) and point number two (-2 dB) the test set applies an offset of -1.5 dB. Be aware that since amplitude offsets are in units of dB, this piece-wise linear interpolation does not produce a linear transition from point to point.

Amplitude Offset

Figure 11.

Amplitude Offset Interpolation



If testing is done outside the range of frequencies bounded by the lowest and highest frequency entries, the test set simply uses the amplitude offset that is paired with the nearest frequency point.

IMPORTANT It is highly recommended that amplitude offsets are set up for each test frequency. This eliminates inaccuracies due to the mismatch between the test set's linear interpolation and the actual frequency response of the RF path between the test set and mobile station.